

# Nano Mechanical Array Signal Processor Program (NMAASP)

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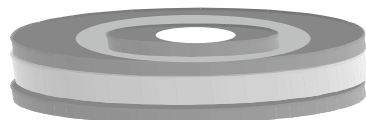


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# Nano-Mechanical Array Signal Processor Program

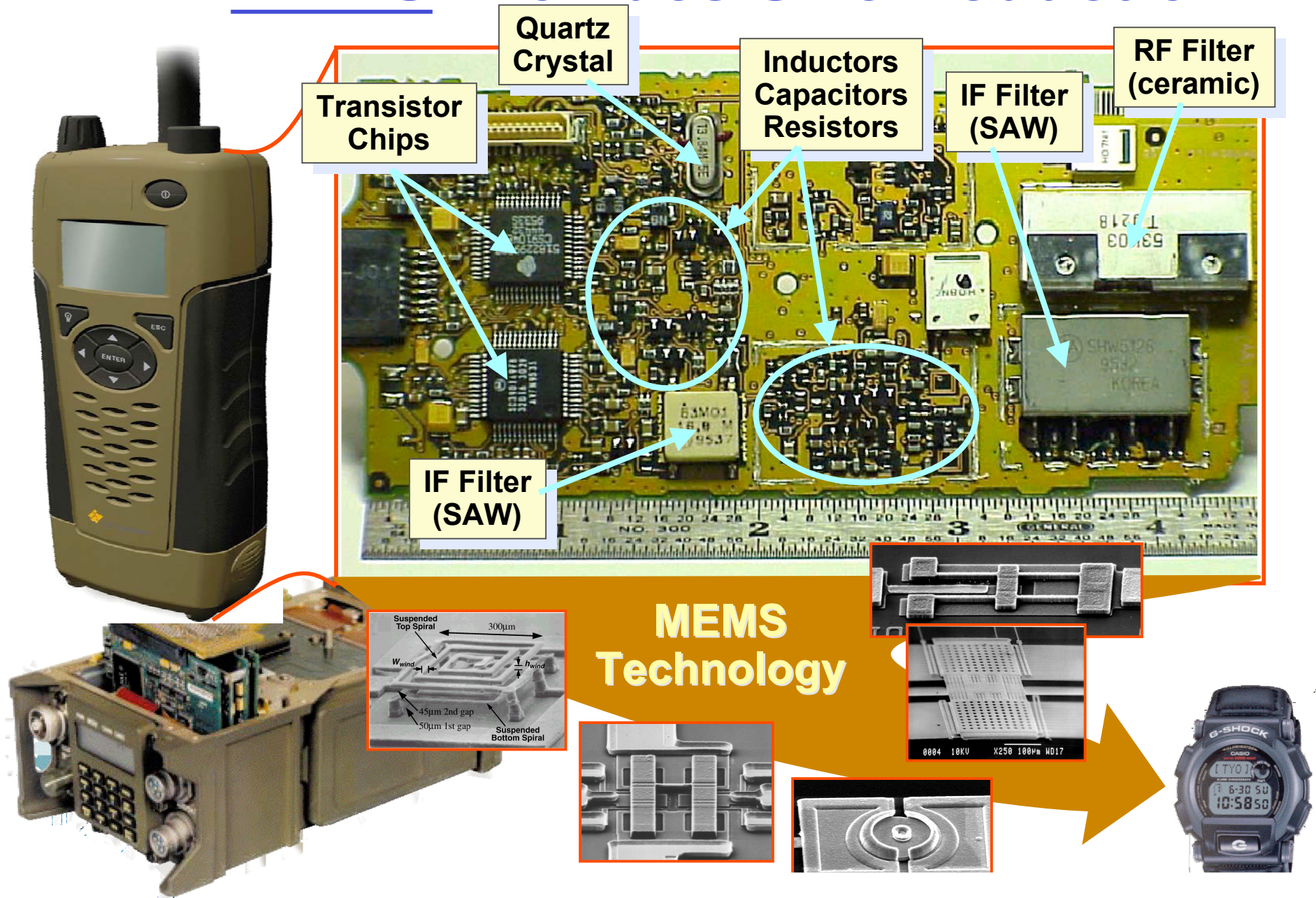


- **Goal:** Create technology for arrays of precision, high  $Q$ , nano mechanical resonators and structures for RF-signal processing (up to 1GHz).
- **Challenges:** Nano-scale precision fabrication, efficient coupling and transduction mechanisms, overcoming loss mechanisms.





# MEMS Provides Size Reduction



# NMASP

- Motivation for Program
  - Enable >100X reduction in size & power consumption & 10X improvement in performance for UHF wireless communication.
- Military Impacts
  - The development of NMASP will enable ultra miniaturized (wristwatch or hearing aid in size) and ultra low power UHF communicators/GPS receivers. Their uses can greatly improve the mobility and location identification of individual war fighters, as well as standalone wireless sensor clusters.

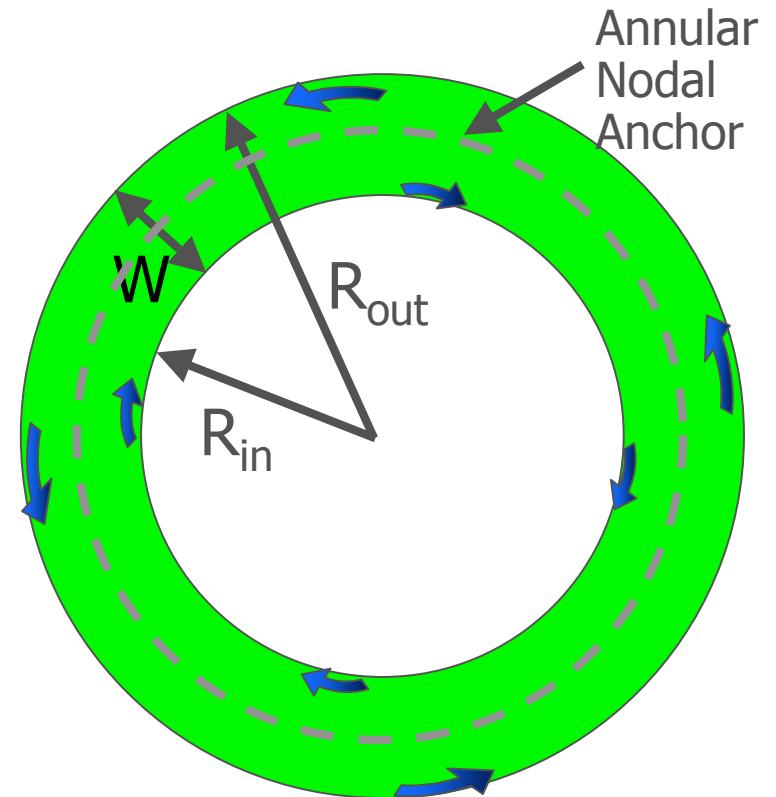
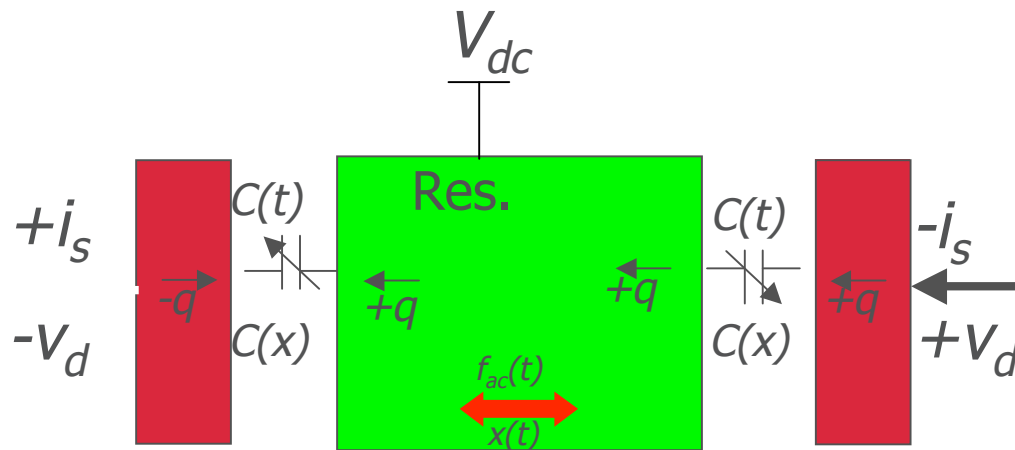


# NMASP

- Start Date: 2001 End Date: 2004
- Program Status: On-Going
  - Precision in material growth technology attained
  - Working on methods for coupling resonators
  - Scaling up arrays of devices
  - Aiming to have some demo's later this year



# Principles of Mechanical Resonators



$$f_{ac} = v_{ac} \cdot V_{dc} \cdot \frac{2C_0}{gap} + \frac{3x^2}{gap^2}$$

$$i_{sense} = X \cdot \frac{2C_0}{gap} + \frac{3x^2}{gap^2}$$

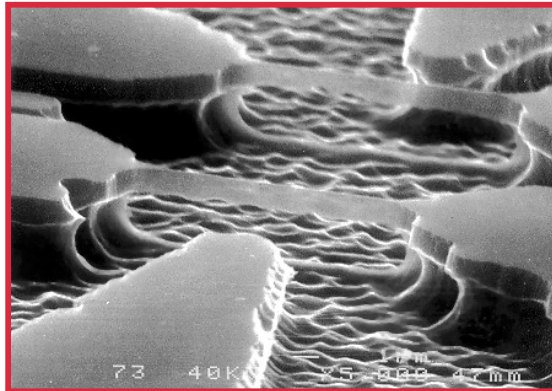
$$f_{SRR} = \frac{1}{2(R_{out} - R_{in})} \sqrt{\frac{G}{\rho}} = \frac{1}{2W} \sqrt{\frac{G}{\rho}}$$



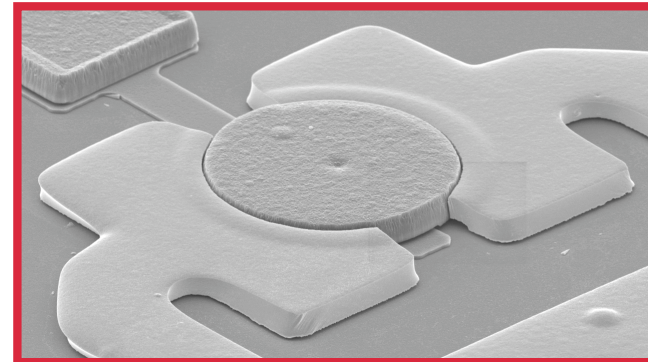


# Nanomechanics and Resonators

- SAW/BAW filters are current state-of-art
  - Resonant frequency strong function of material thickness
  - Large devices, separately packaged
- MEMS processes offer ability to fabricate resonant beams and structures
  - High resonant frequencies with low force constants ( $f$  goes as  $W/L^2$ )
  - Small length, width, but also small gaps ( $R$  goes as  $\text{gap}^4$ )



**Caltech 330 nm-wide twin resonators**  
 $(f_0 = 70.7 \text{ MHz}, Q = 20,000)$



***U. Michigan radial polysilicon***  
 $f_0 \sim 200 \text{ MHz}, Q \sim 20,000$

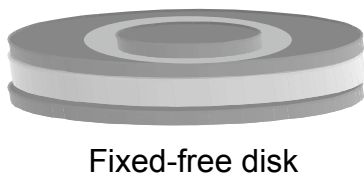


# Why Nano-Resonator Filters?

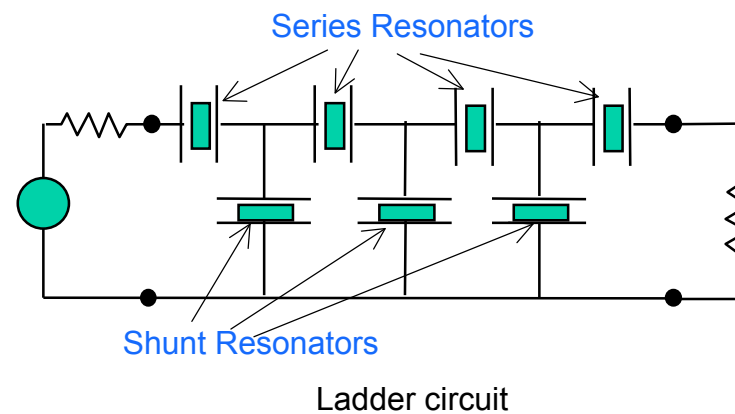
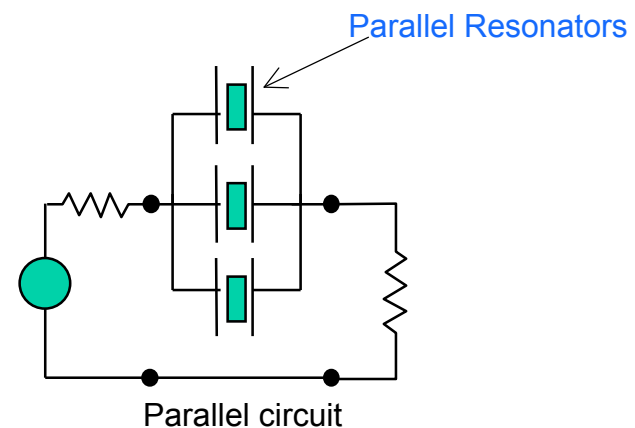
- Integrated resonators that implement high-Q filter functions with *huge* reductions in power and volume
- Arrays of resonators that allow analog spectrum generation and analysis
- Enable new transmitter and receiver architectures: *secure, ultra-low power, multi-standard communications!*



## Resonator Topologies

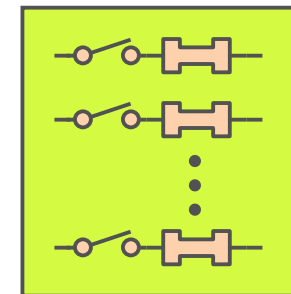
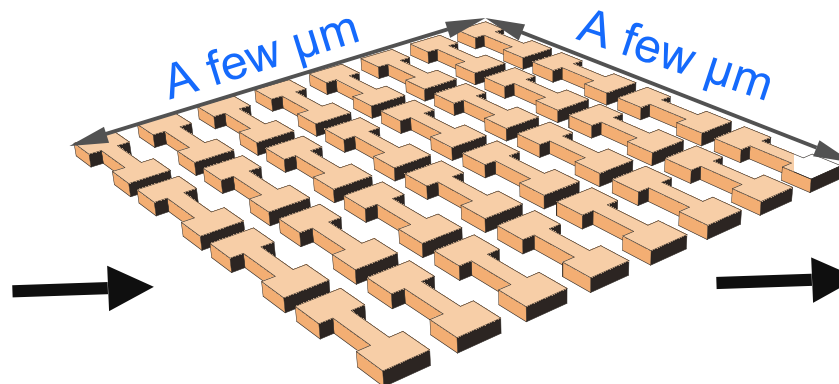
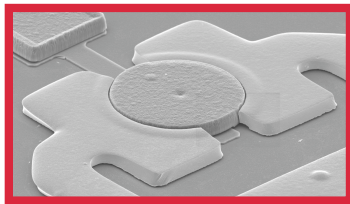
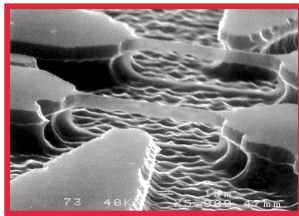


## Filter Topologies



# Approach

- Silicon-based process technologies (GA Tech, Michigan, CMU, UCB)
- Piezoelectric (U. MD/Northrop, Honeywell, JPL, Draper, HRL, UCSB)
- Carbon Nanotubes (JPL/Brown, UCI)
- Arrays and Interconnections
- RF Architectures



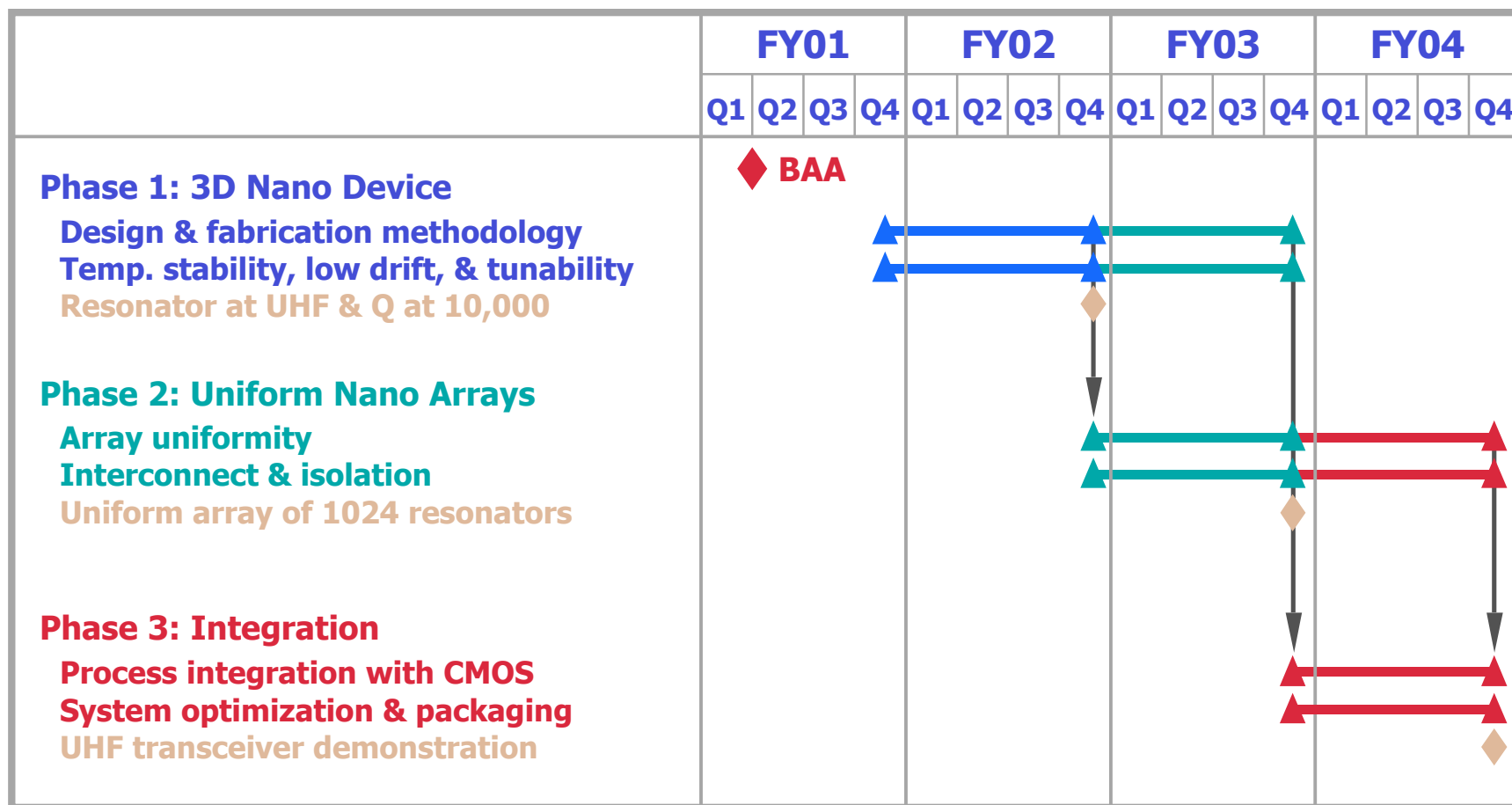
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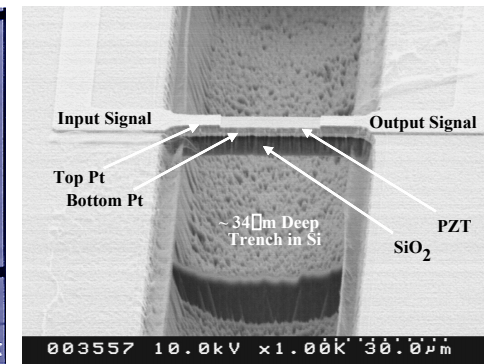
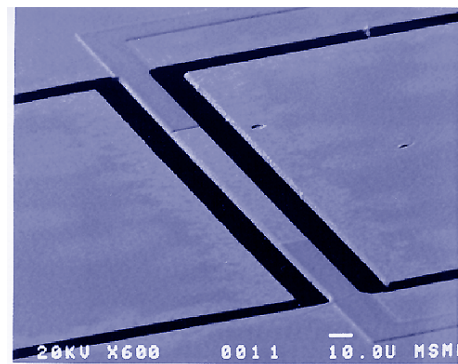
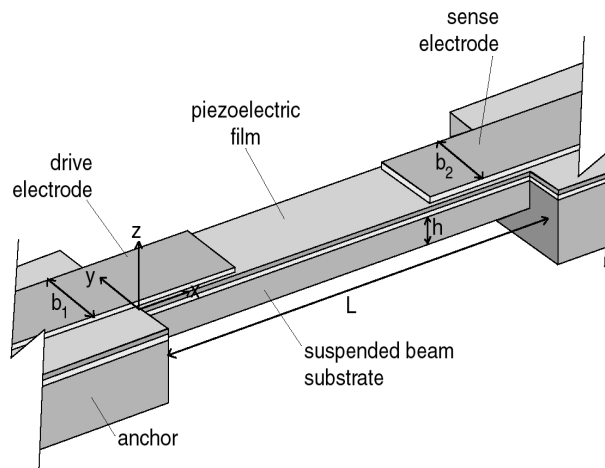
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# NMASP Program Schedule



# Piezoelectric Resonators



- ZnO and PZT resonators demonstrated (UMd)
- Unsatisfactory performance due to poor Q and ultimate frequency limits

- **Good electromechanical scaling to microwave frequencies**  
( $\propto^{-1/2}$  for piezoelectric vs  $\propto^{-5/2}$  for capacitive)
- **Good microfabrication scaling (strain-based vs. displacement-based)**
- **Low-voltage operation (CMOS levels and below)**



# Why AlN? AlGaAs?

	AlN	Al <sub>0.3</sub> Ga <sub>0.7</sub> As	GaN	BN
$v_{11}$ [m/s]	11270	4934	7900	15400
$K^2$ ( $d_{31}$ mode)	0.26	0.02	0.02	0.16
$Q$	9.14	12.0	9.7	7.1

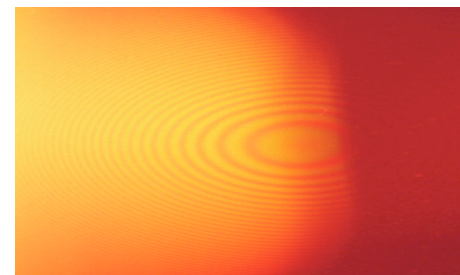
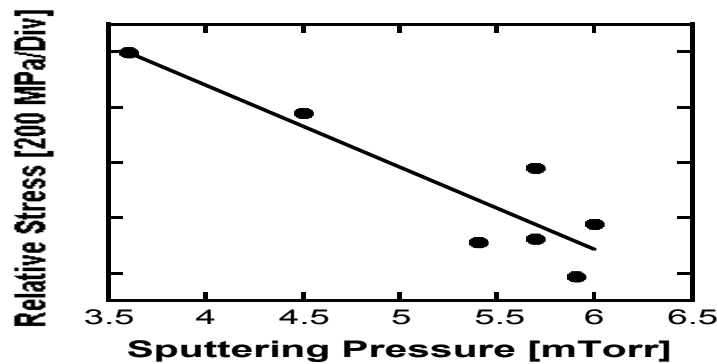
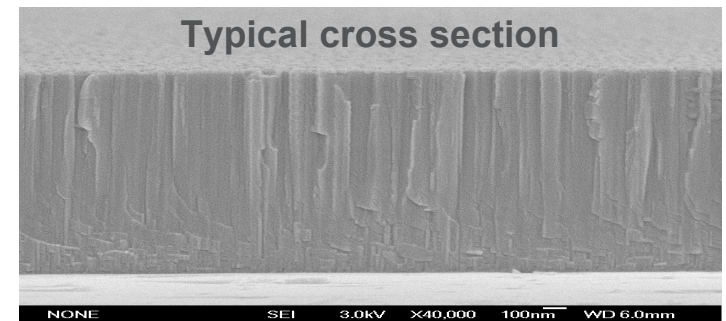
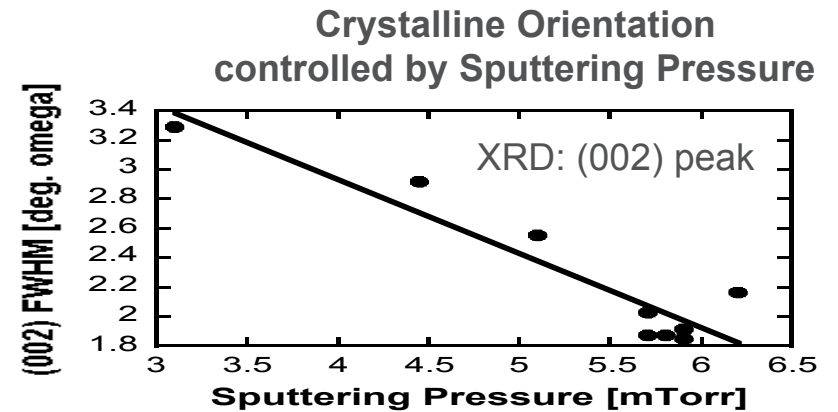
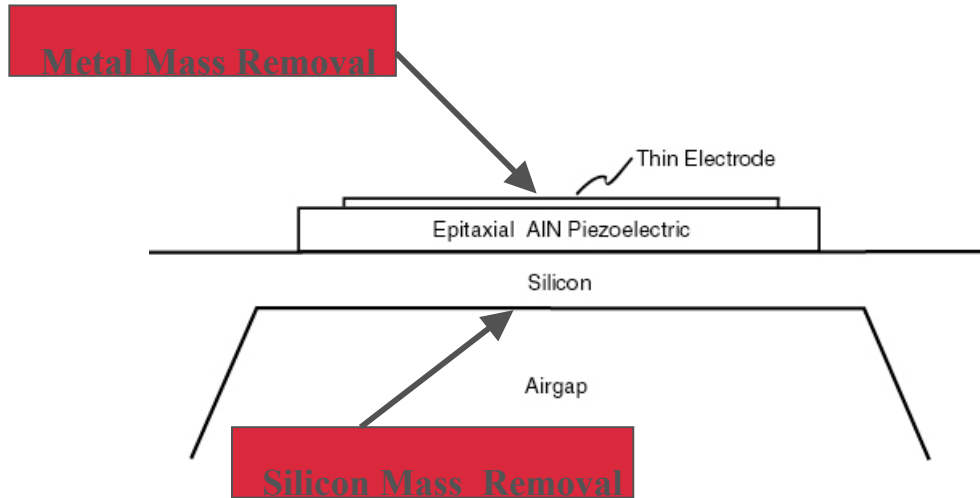
## ■ AlN:

- Excellent figures of merit
- Strong potential for near-term discrete-chip filters

## ■ AlGaAs:

- Lower figures of merit, but:
- Well characterized epitaxial processing for high quality single-xtal films
- Integration with high-speed electronics and optoelectronics
- Directly implementable in standard HEMT processes

# NMASP Materials: AlN on Silicon



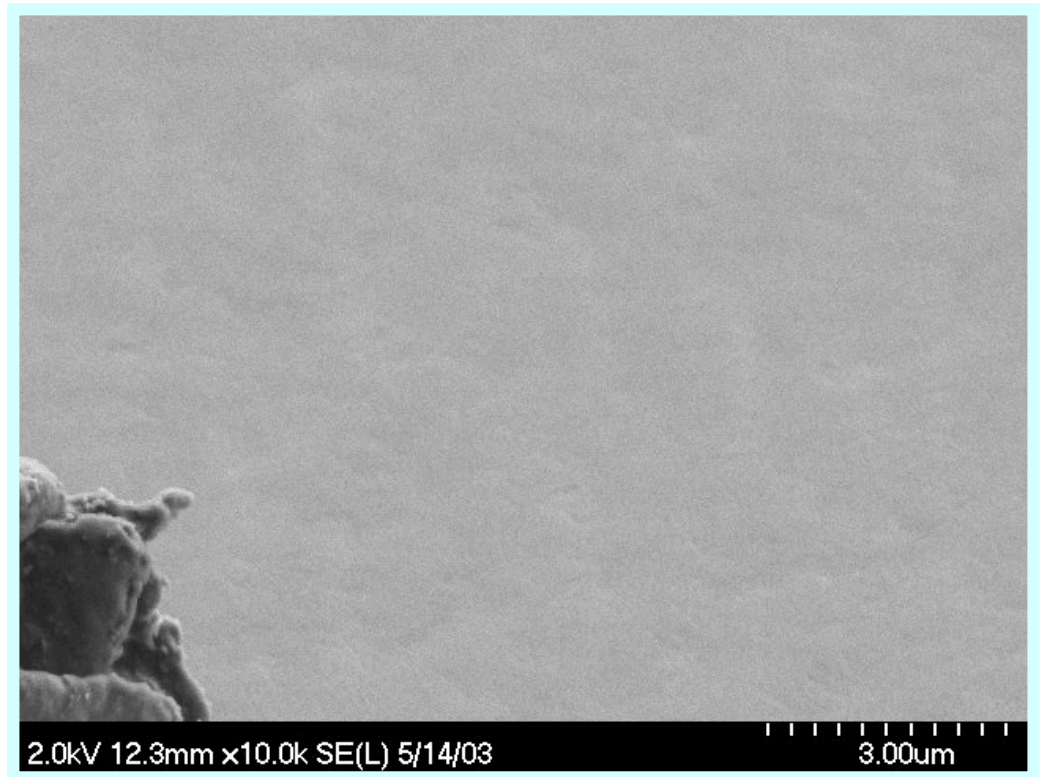
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# Precision Growth of GaN at Honeywell

- Highly Uniform GaN film ( $< 1\%$  thickness non-uniformity across a 4" wafer)
- High resistivity GaN film ( $> 20 \text{ MOhm/square}$ )
- Seed layer developed (minimized pitting)
- GaN resonator layer developed (2 micron thick layers without cracking)



Blanket single crystal film, 1 micron thick, grown on 4 inch diameter Si wafers. Thickness and roughness controlled within few nanometers (*dust speck is necessary for focus on the mirror surface*)



# Alternate materials

Material	Young's Mod. GPa	Density kg/m <sup>3</sup> 10 <sup>3</sup>	Thermal Cond. W/m K 10 <sup>2</sup>	Thermal Expansion 10 <sup>-6</sup> /K	Specific Heat J/kg – K 10 <sup>3</sup>	Diff. K <sup>2</sup> /C <sup>2</sup>	$\frac{E_u^2 T_u}{C_u} / 10^{-4}$
<b>Silicon*</b>	<b>166</b>	<b>2.3</b>	<b>1.57</b>	<b>2.3</b>	<b>0.668</b>	<b>2.35</b>	<b>1.55</b>
<b>Diamond*</b>	<b>1076</b>	<b>3.5</b>	<b>20.00</b>	<b>1.0</b>	<b>0.472</b>	<b>42.4</b>	<b>1.8</b>
SiC*	700	3.2	3.50	6.4	0.8	4.4	30.6
GaAs*	75	4.9	0.46	6.9	-	-	~3
Al <sub>2</sub> O <sub>3</sub>	275	3.62	0.36	6.57	0.8	.45	11.1
SiO <sub>2</sub> (amorphous)	70	2.5	0.014	0.5	1.0	.014	.02
Quartz*	100	2.6	0.1	0.55	.787	.127	.04
Si <sub>3</sub> N <sub>4</sub>	255	3.1	0.19	2.8	0.7	0.27	3.8



single crystal

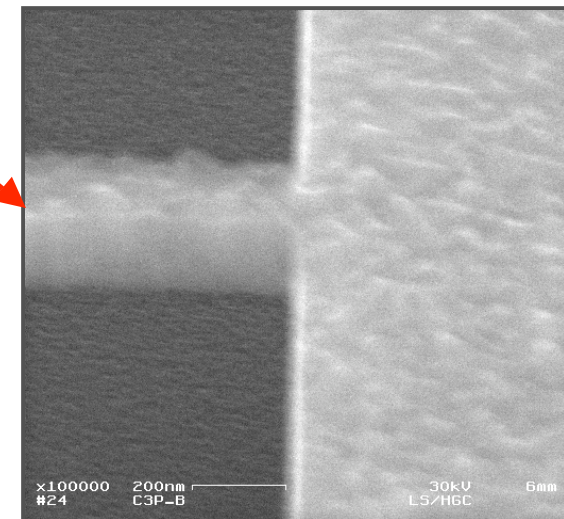
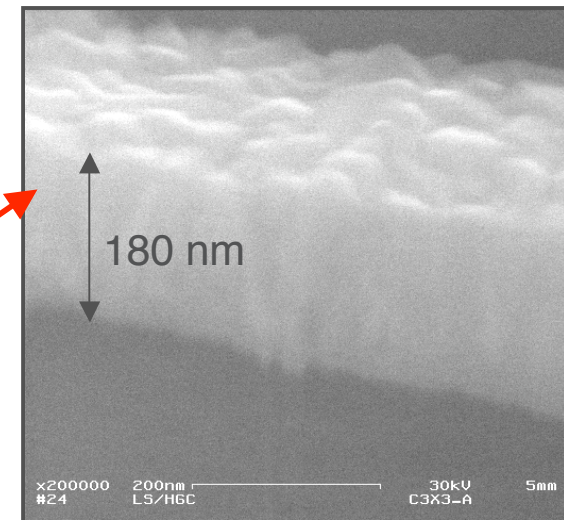
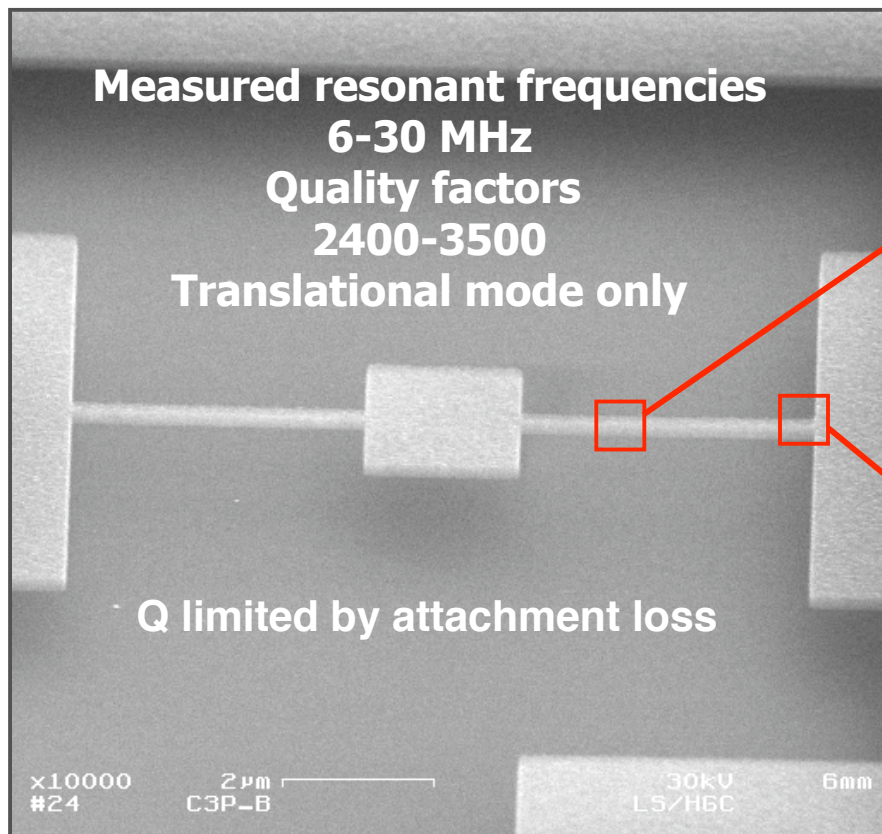
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# CVD Diamond “MEMS Paddle”



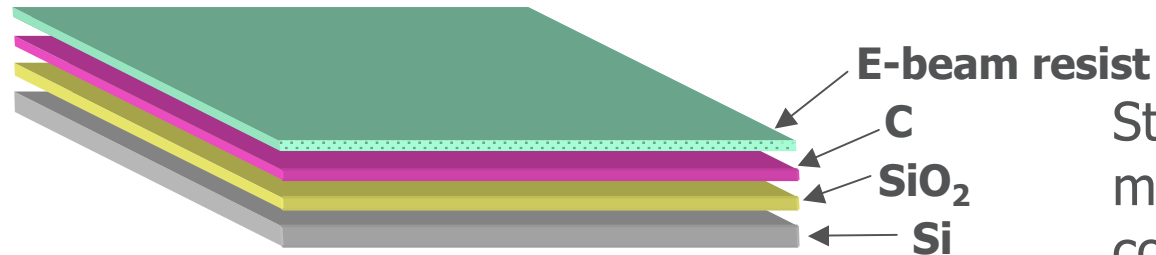
**L. Sekaric – Cornell**

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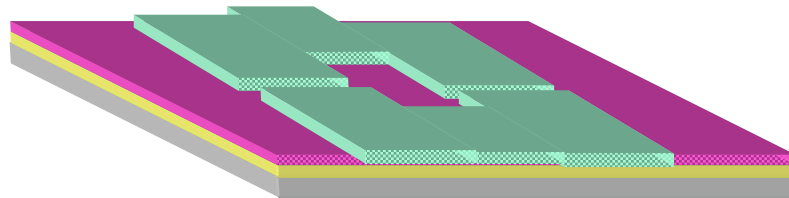
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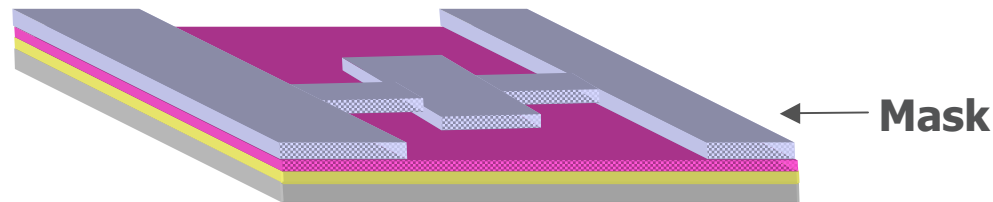
# CVD Diamond Fabrication



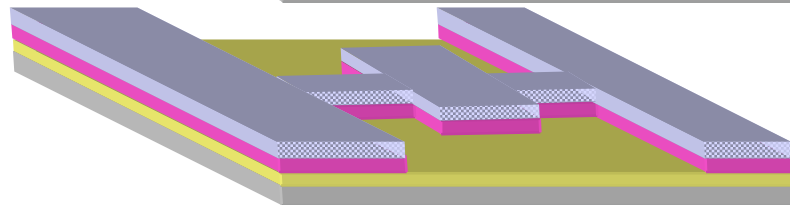
Start: CVD deposited material on oxide coated wafer



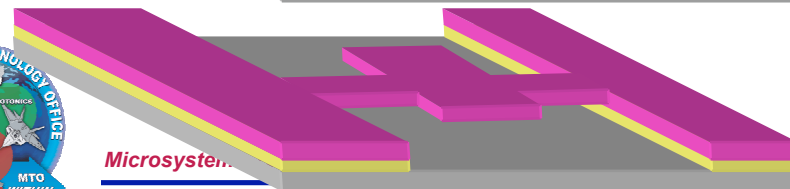
E-beam lithography and development



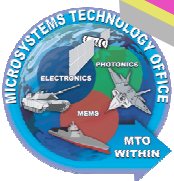
Metal mask deposition and lift-off



RIE etching



Release (in BHF)



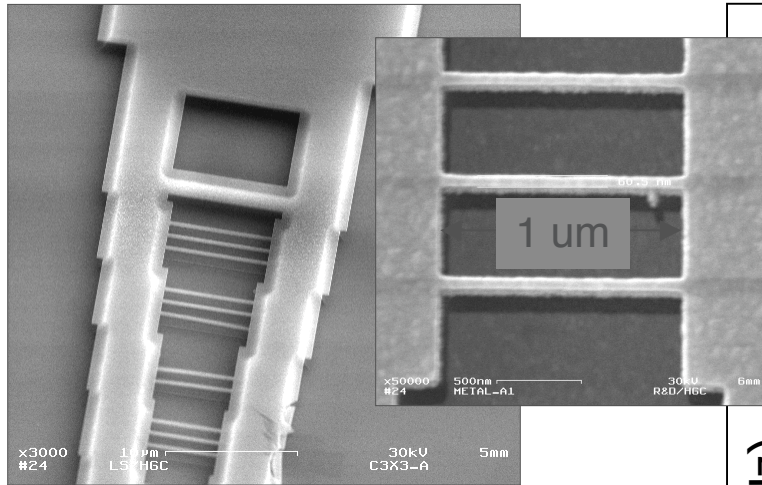
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# Results: doubly clamped beams



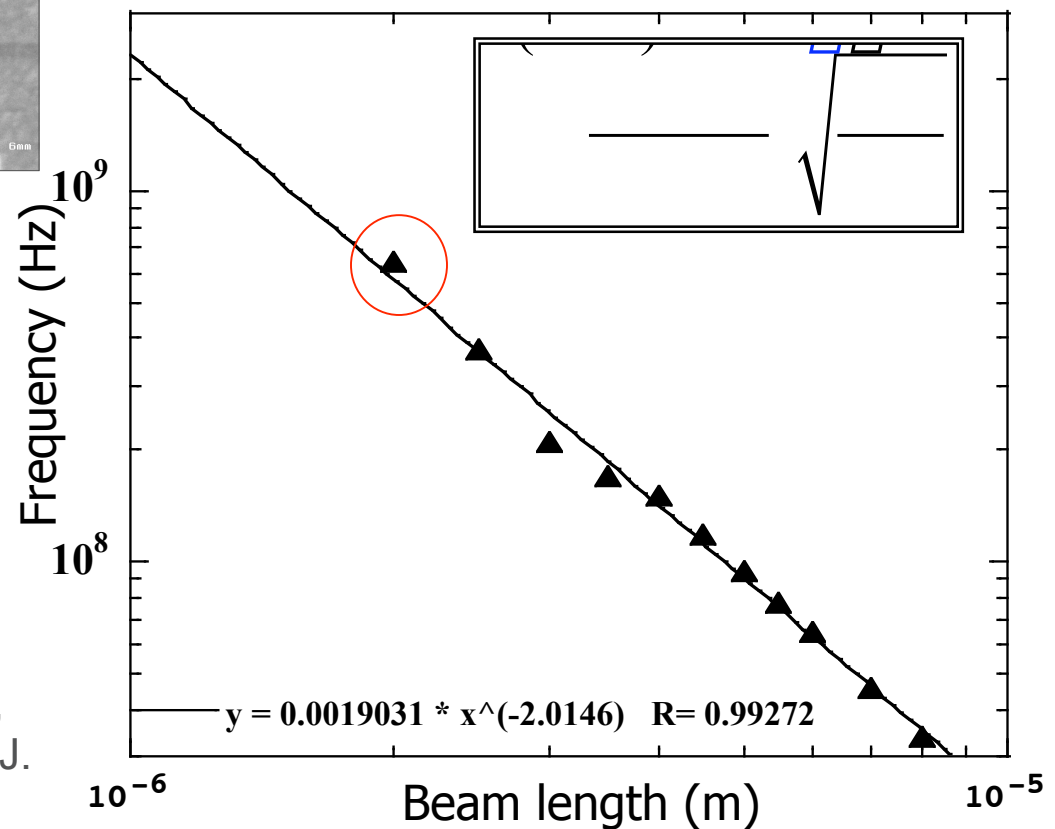
Resonant frequencies  
measured up to

**640 MHz**

**Q~1000**

L. Sekaric, J. M. Parpia, H. G. Craighead,  
T. Feygelson, B. H. Houston, J. E. Butler J.  
Appl. Phys. (Dec. 2002)

Beam frequency vs. length



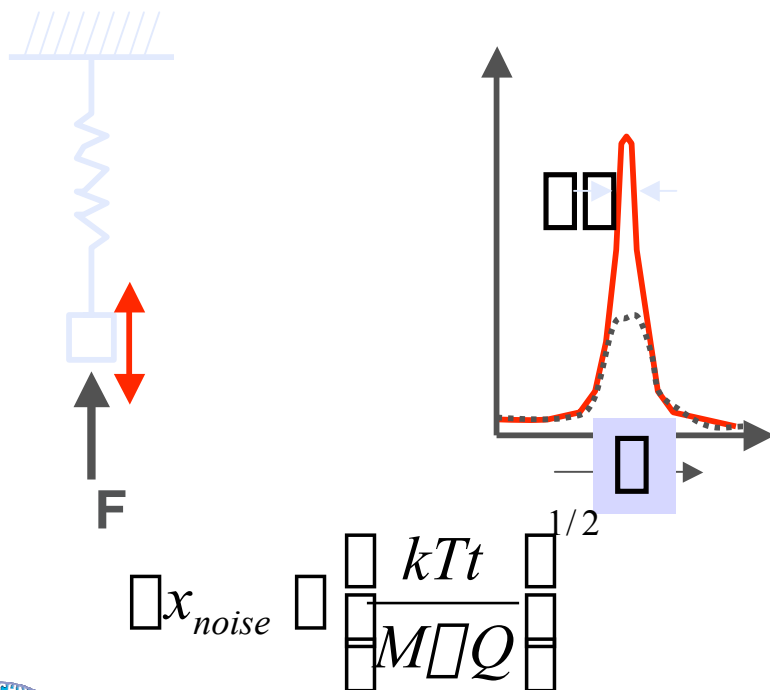
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# Energy Dissipation in NEMS

$$\frac{1}{Q_{total}} = \frac{1}{Q_{air}} + \frac{1}{Q_{boundary}} + \frac{1}{Q_{TED}} + \frac{1}{Q_{bulk}} + \frac{1}{Q_{Surface}}$$



Contributing processes:

- metal films
- viscous friction
- acoustic radiation
- boundary losses
- processing induced damage
- thermoelastic dissipation
- surface effects (**not just roughness**)
- other?

Fluctuation Dissipation Theorem

What are the fundamental limits?

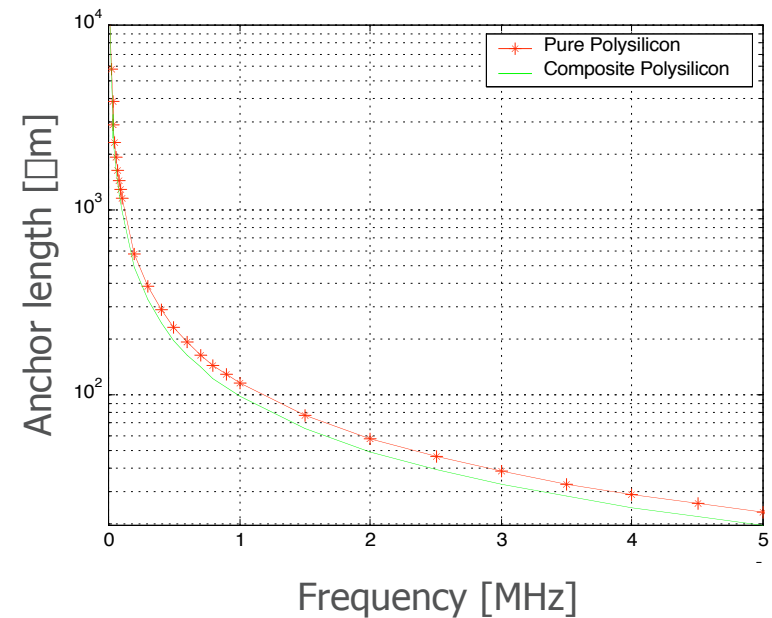
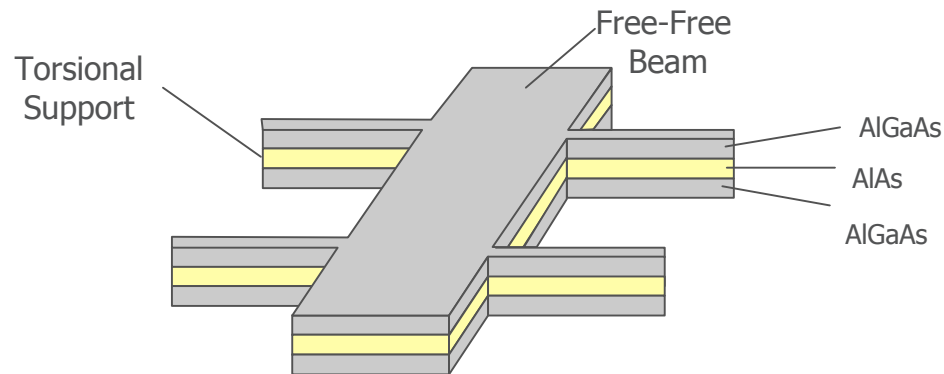


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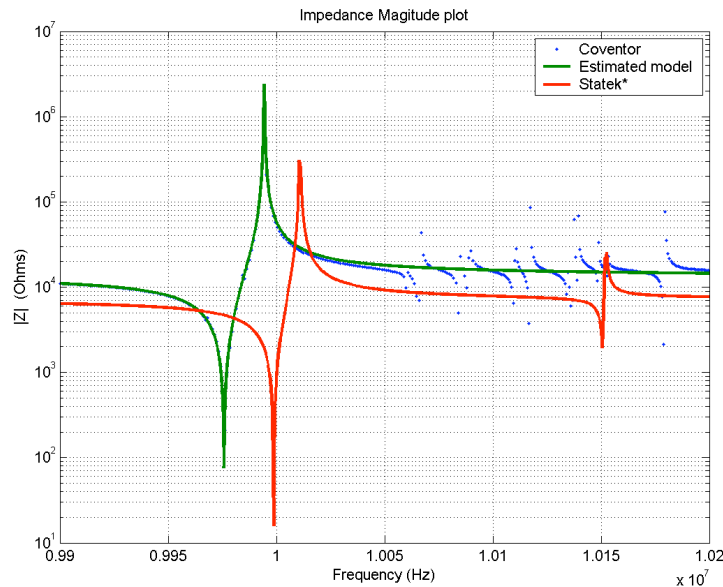
# Modeling and Design: free-free resonators



- Initial model validation complete
- Devices for full model validation currently in fab
- Low-frequency (up to 250MHz) filter fab run scheduled for mid-August



# Benchmarking New 3-D Software with Experimental Quartz Resonator Data



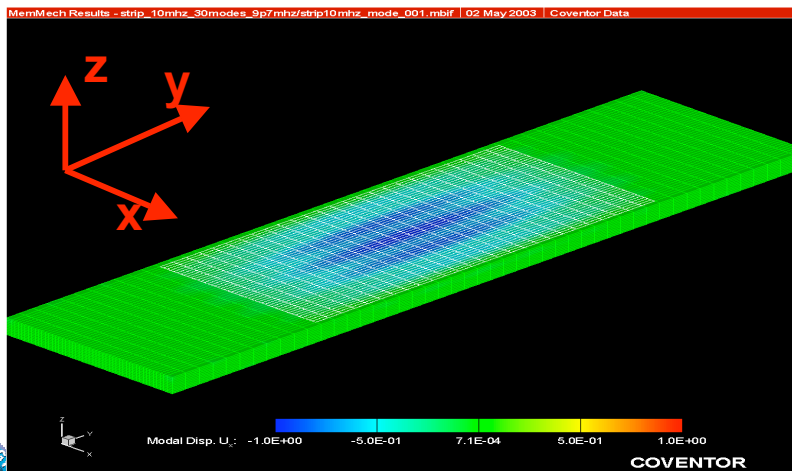
## Details:

- 10 MHz TS mode AT-cut quartz strip resonator by Statek
- Analysis tool: beta version of commercial FEA software (Coventor)
- Compare FEA to measurements made by Statek
- Benefits: Demonstration of a high degree of correlation provides confidence in the new tool

## Equivalent circuit elements:

- Experimental data:  
 $C_0 = 2.24 \text{ pF}$ ,  $C_1 = 5.45 \text{ fF}$ ,  $R_1 = 15.5 \Omega$
- Numerical analysis:  
 $C_0 = 1.17 \text{ pF}$ ,  $C_1 = 4.36 \text{ fF}$ ,  $R_1 = 75.5 \Omega$

\*Statek measurements provided by Greg Burnett

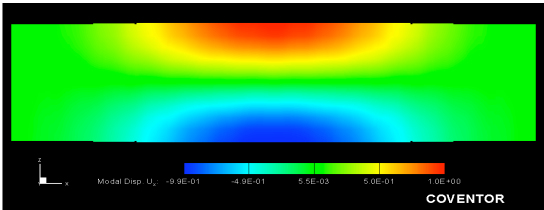
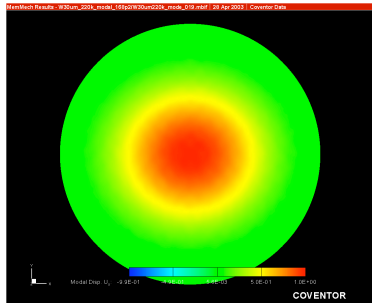
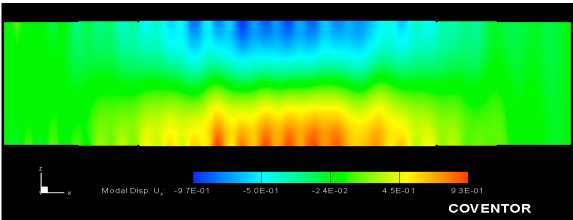
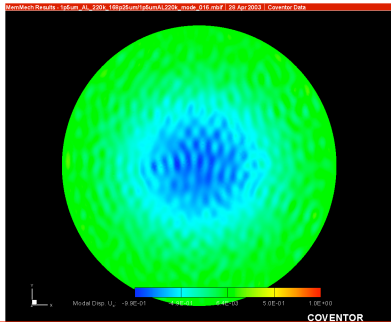
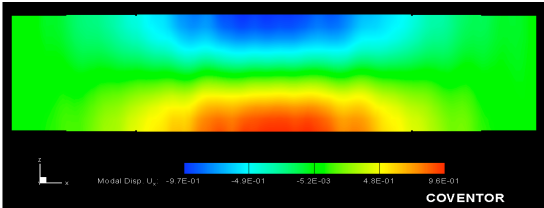
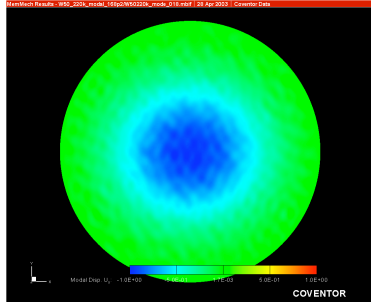


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# Energy Trapping vs. Electrode Width - Optimizing Q

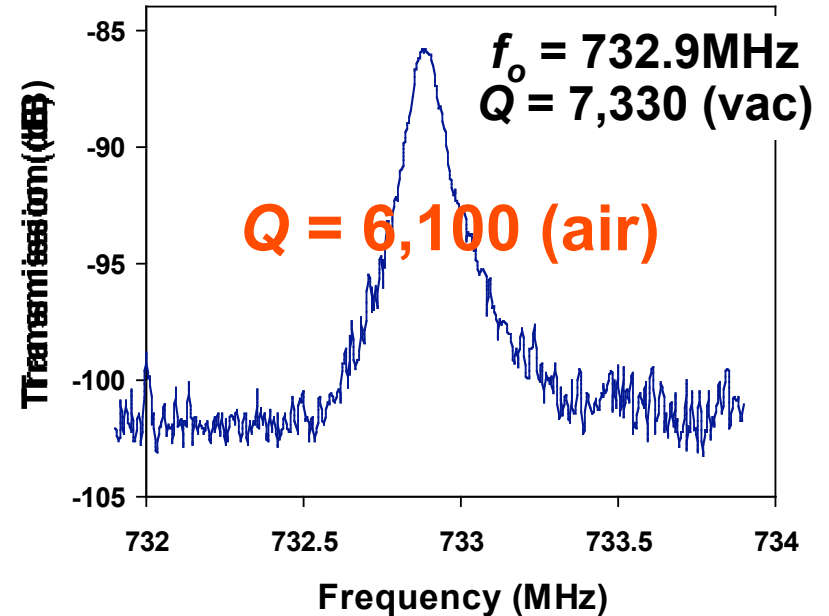
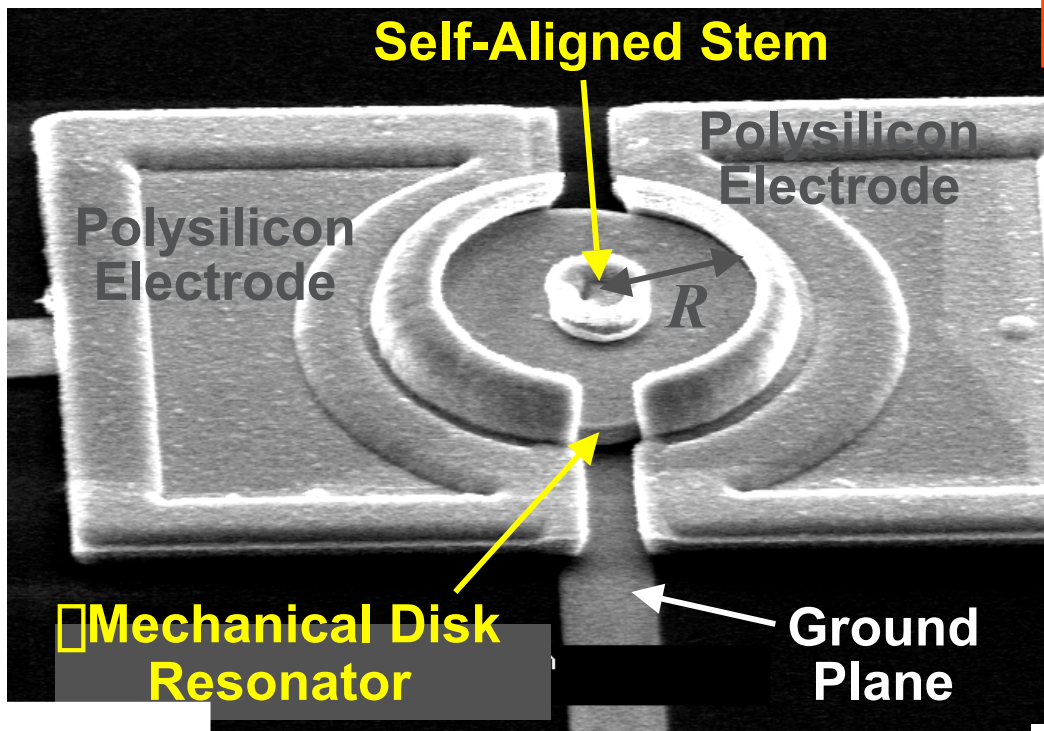
Electrode width	Cross-section view (X-Z)	Top view (X-Y)	Remarks
30 $\mu\text{m}$			<ul style="list-style-type: none"> <li>• Best trapping under resonator area</li> <li>• little flexural component</li> </ul>
40 $\mu\text{m}$			<ul style="list-style-type: none"> <li>• large flexural component</li> </ul>
50 $\mu\text{m}$			<ul style="list-style-type: none"> <li>• trapping not confined to resonator but extends under electrodes</li> </ul>



# 733 MHz Self-Aligned Radial Contour-Mode Disk Mechanical Resonator

- Self-aligned stem for reduced anchor dissipation
- Polysilicon electrodes for better gap stability
- $Q > 6,000$  seen even in air (i.e., atmospheric pressure)!
- Below: 20  $\mu\text{m}$  diameter disk

**Design/Performance:**  
 $R=10\mu\text{m}$ ,  $t=2.1\mu\text{m}$ ,  $d=800\text{\AA}$ ,  $V_p=6.2\text{V}$   
 $f_o=732.9\text{MHz}$  (2<sup>nd</sup> mode),  $Q=7,330$



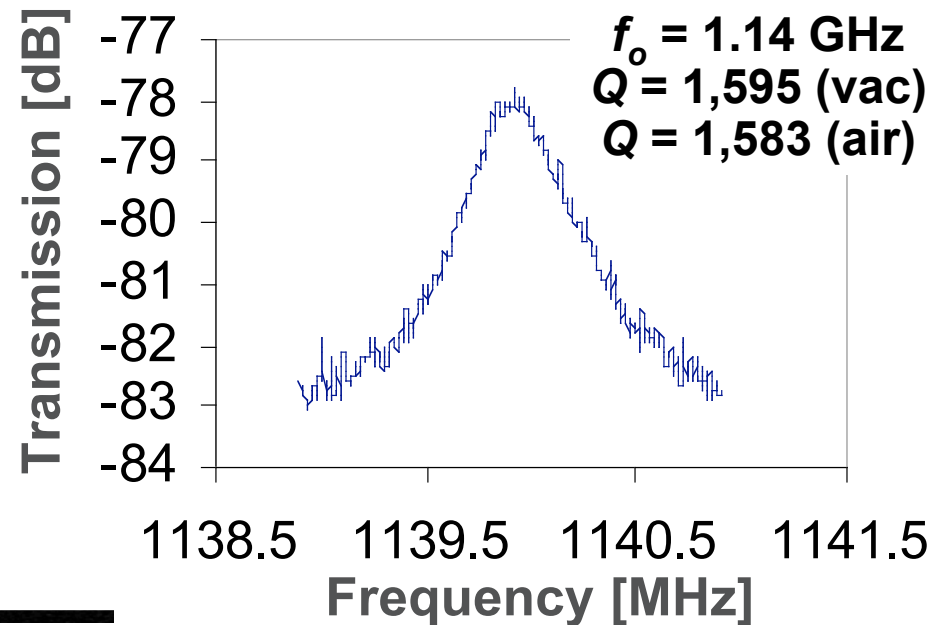
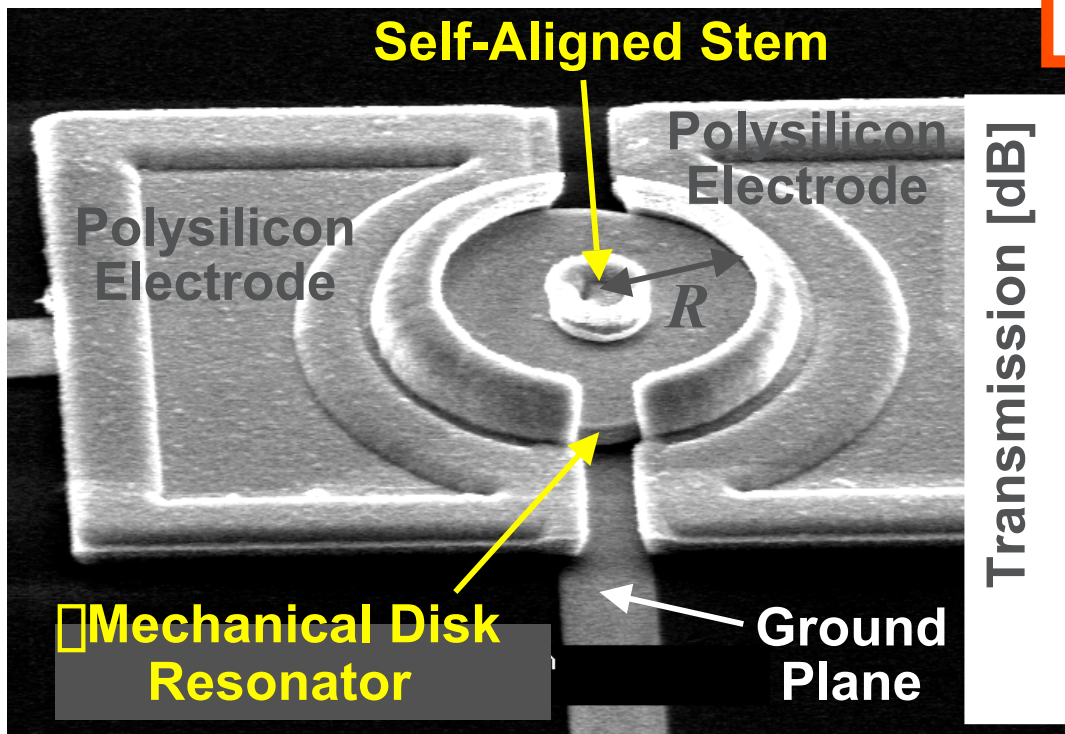


# 1.14-GHz Self-Aligned Radial Contour-Mode Disk Mechanical Resonator

- Self-aligned stem for reduced anchor dissipation
- Operated in the 3<sup>rd</sup> radial-contour mode
- $Q > 1,500$  seen even in air (i.e., atmospheric pressure)!
- Below: 20  $\mu\text{m}$  diameter disk

## Design/Performance:

$R=10\mu\text{m}$ ,  $t=2.1\mu\text{m}$ ,  $d=800\text{\AA}$ ,  $V_p=6.2\text{V}$   
 $f_o=1.14\text{ GHz}$  (3<sup>rd</sup> mode),  $Q=1,595$

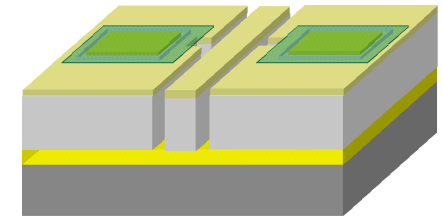
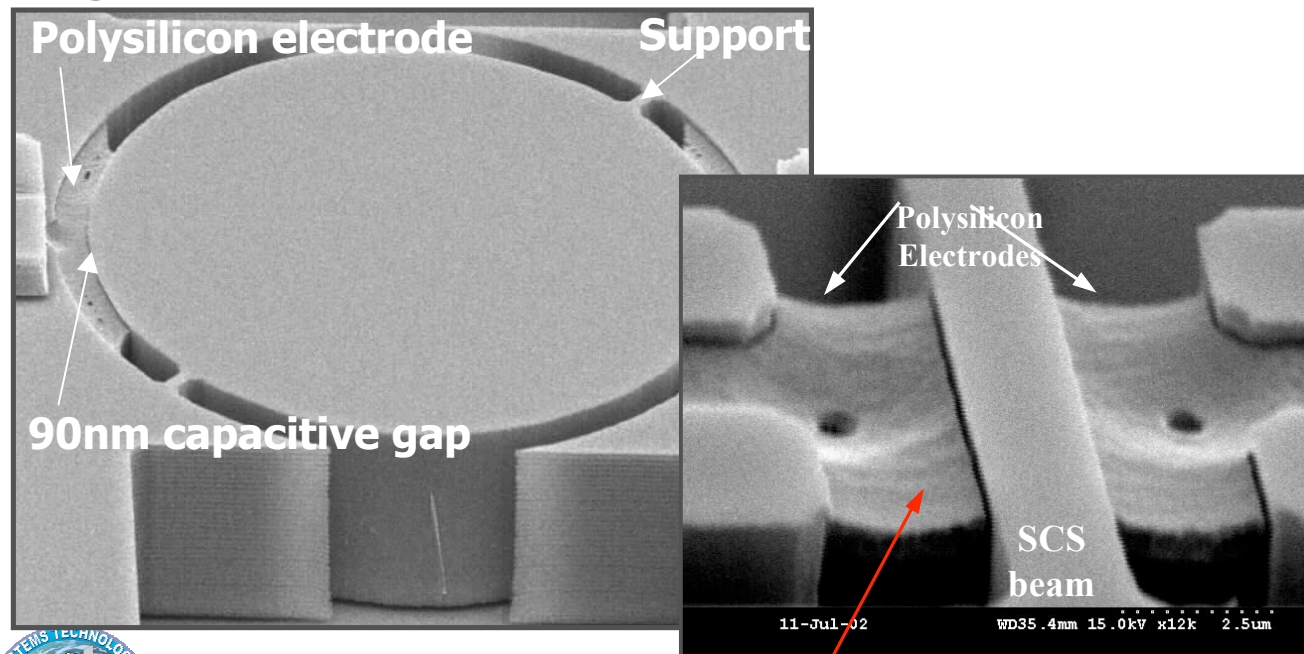


[U. Mich., 2003]

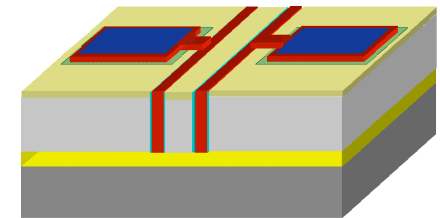
# VHF and UHF Resonators

## ❑ SOI-Based HARPSS Technology

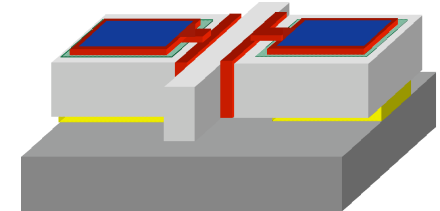
- 10-30 micron thick films
- Ultra-stiff resonators with high width to height ratio
- Results in smaller equivalent resistance → larger SNR



*Pad oxide and LPCVD nitride for insulation. Trenches define resonator boundary.*



*LPCVD sacrificial oxide and polysilicon. Polysilicon patterned, Metallization*

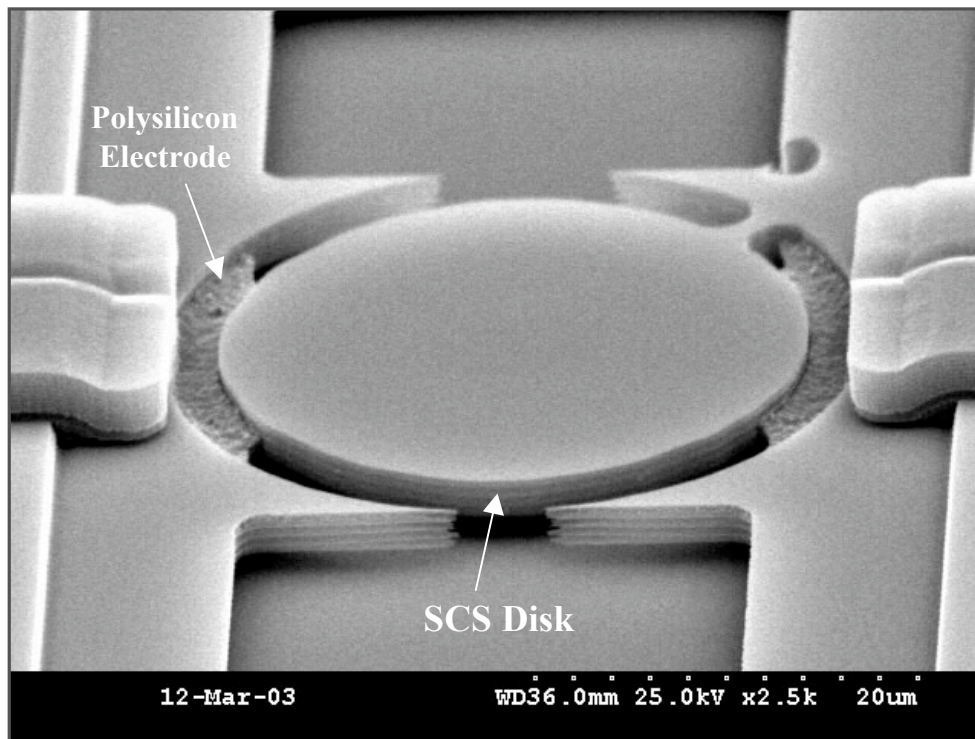


*Electrode polysilicon patterned release openings etched in SCS. Release and undercut in HF:H<sub>2</sub>O*

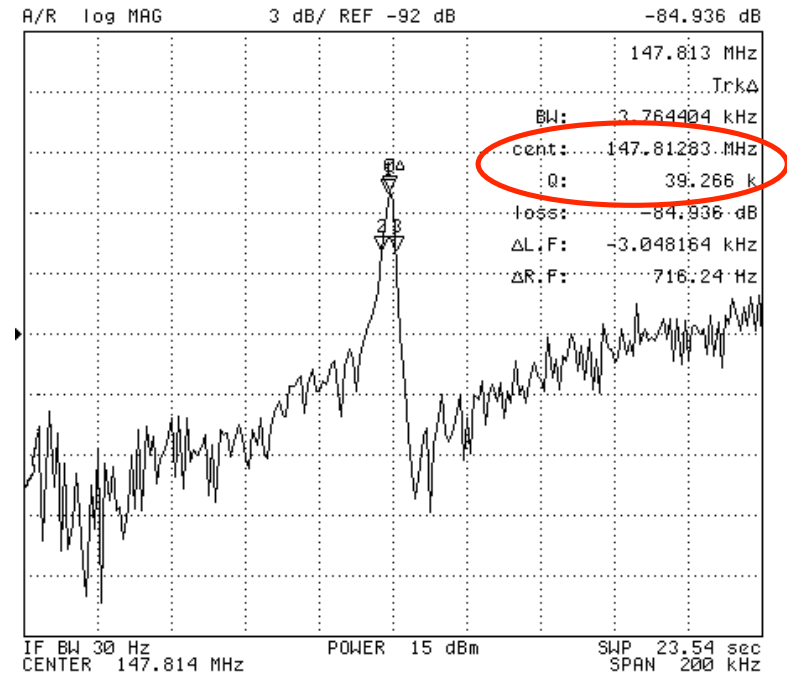




# Single Crystal Silicon Disk Resonators



side-supported SCS disk resonator  
 90nm capacitive gaps  
 Diameter=30  $\mu$ m, Thickness =3  $\mu$ m



**Q=40,000 @ 147.8MHz**



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# TCF of Capacitive HARPSS Resonators

## □ Temperature Coefficient of Frequency

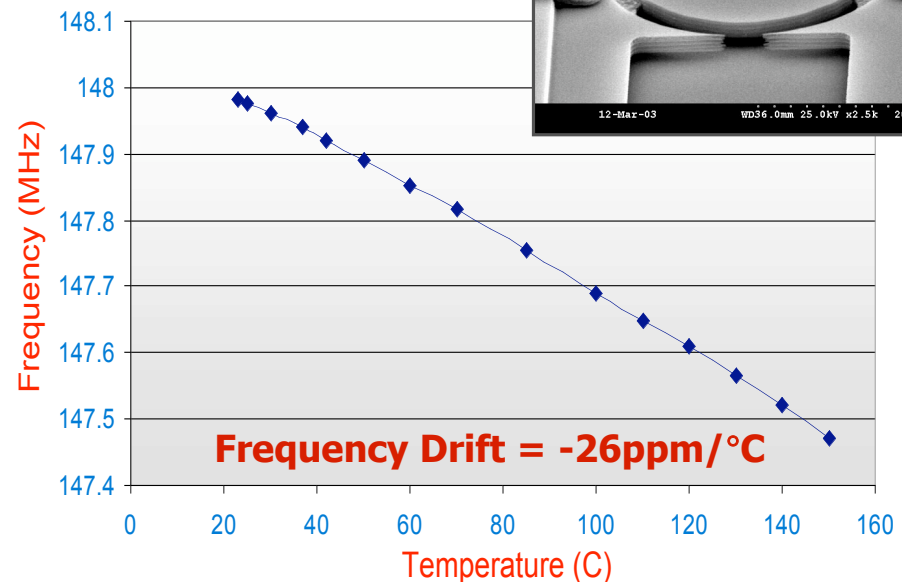
- Temperature dependency of the resonating material's Young's modulus will be the dominant contributing factor.
- Thermal Expansion □ Dimensional Change

Mechanical  
Stiffness

Electrical  
Stiffness

$$\frac{1}{f} \cdot \frac{\partial f}{\partial T} = \frac{1}{2} \cdot \frac{1}{E} \cdot \frac{dE}{dT} \square \frac{1}{R} \cdot \frac{dR}{dT} \square \frac{3V_p^2 A_e \square}{Kg^3} \cdot \frac{1}{g} \cdot \frac{dg}{dT}$$

*Dominant term*

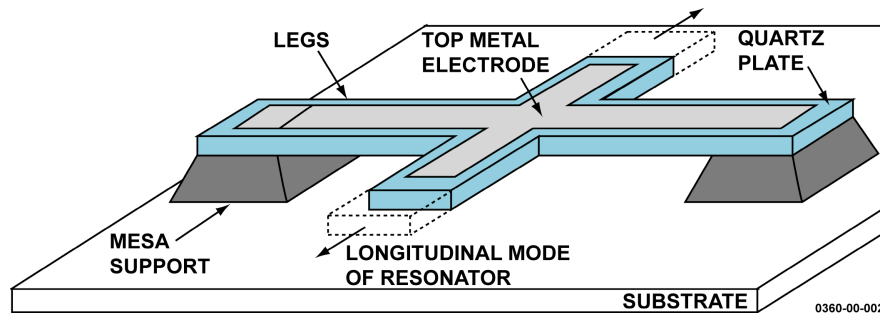


**Measured temperature characteristic for the 150MHz disk resonator**

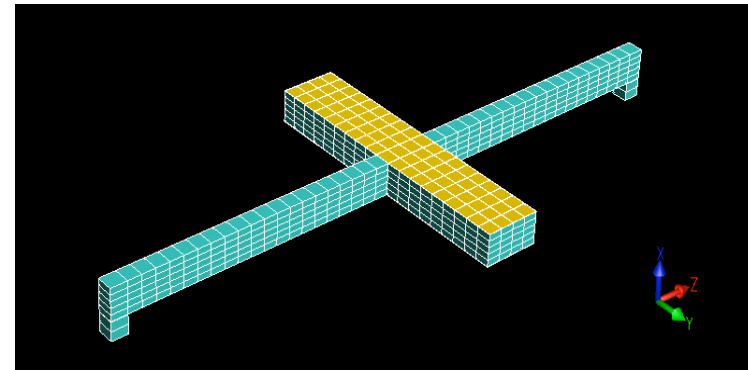


# Alternate Designs for Large Arrays

- Using the same fabrication process, designs which rely only on lateral dimensional changes can be fabricated in temperature compensated X-cut quartz



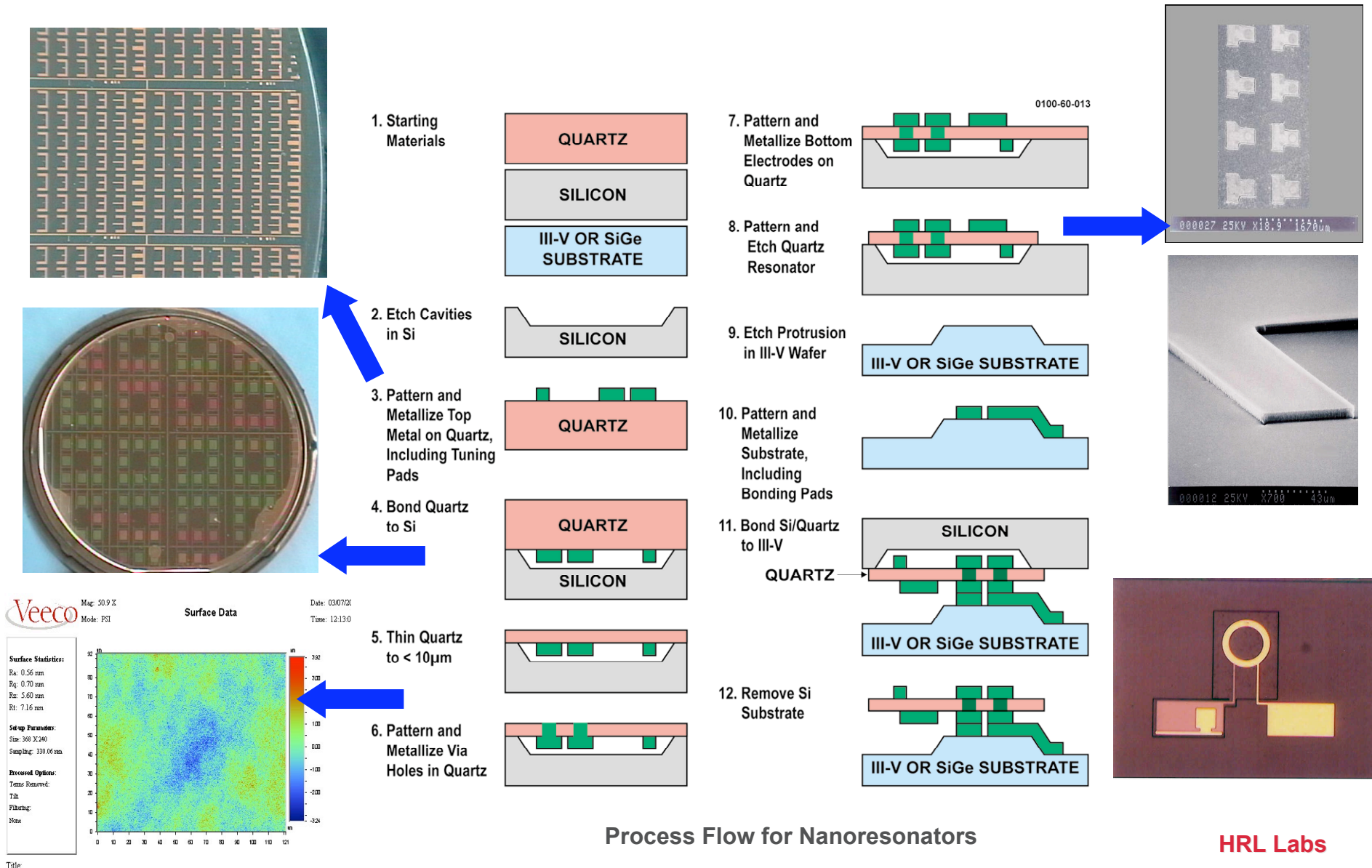
For 300 MHz: resonator length  $L \sim 10 \text{ } \mu\text{m}$   
(resonant frequency scales like  $1/L$ )



Meshed longitudinal design in 3-D Simulator



# Integrated Thin Film Quartz Resonators

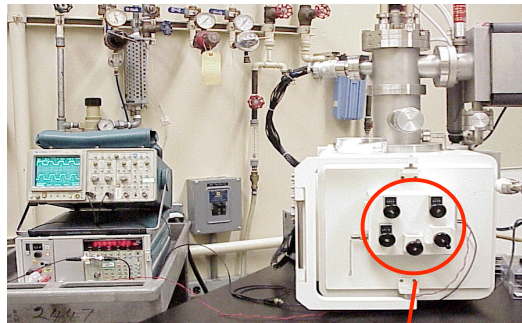


Process Flow for Nanoresonators

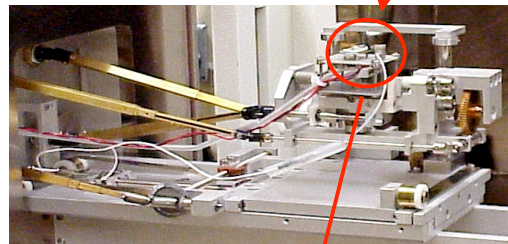
HRL Labs



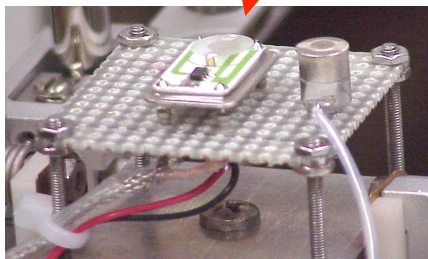
# FIB Frequency Tuning During Real-Time Monitoring



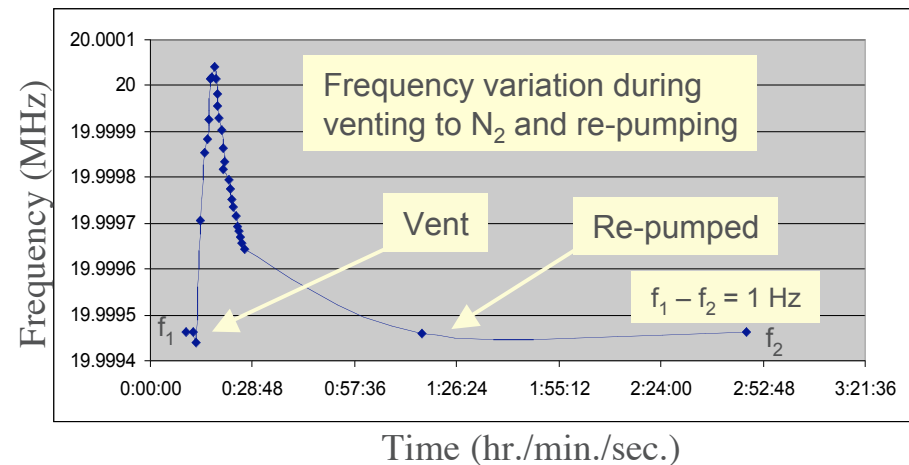
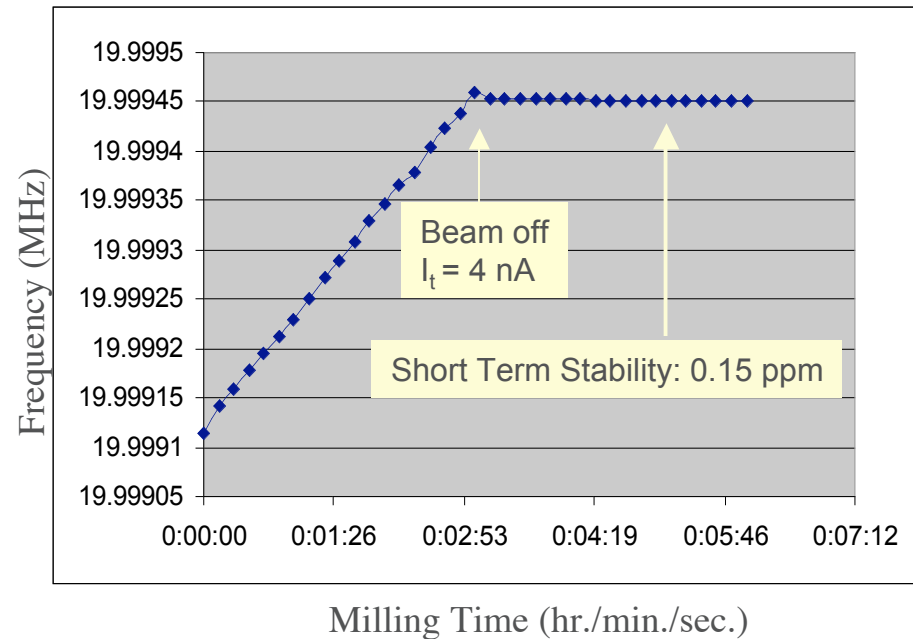
FIB System



FIB Chamber



Commercial 20-MHz Shear-Mode Oscillator



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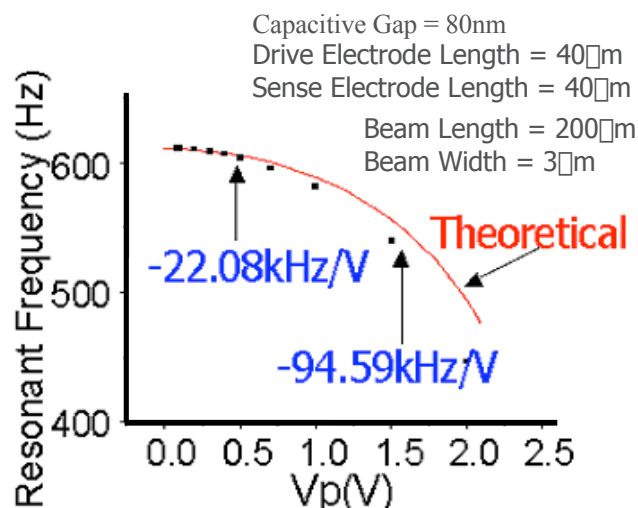
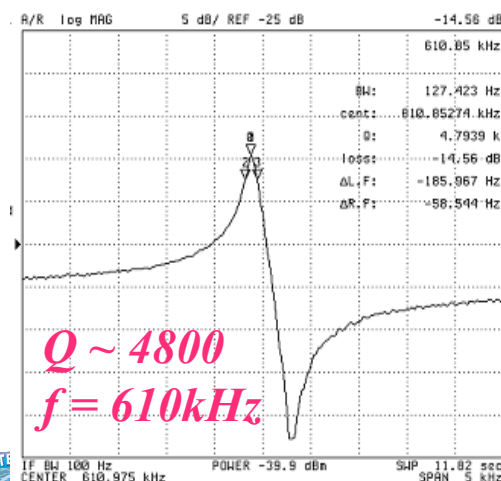
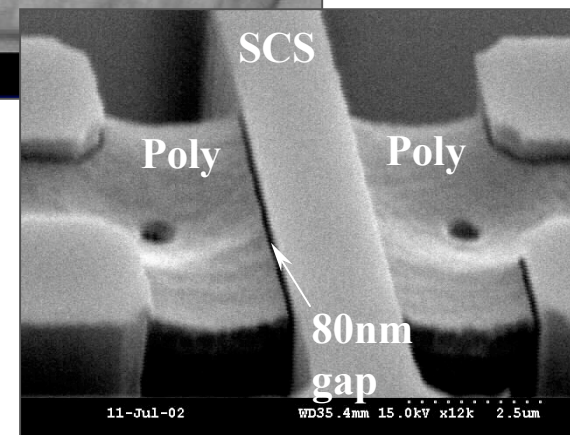
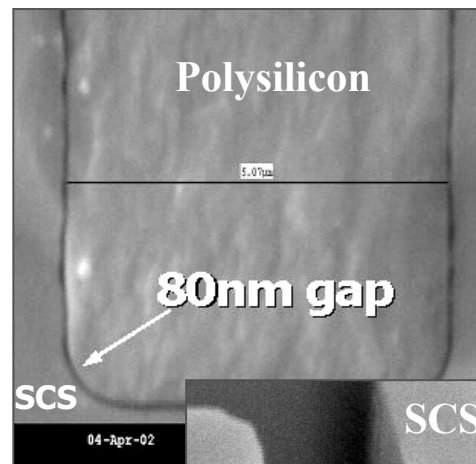
# Nanometer Capacitive Gaps

- ❑ **Self-aligned** vertical capacitive gaps defined by the sacrificial oxide layer

→ Potentially reducible to 10nm

$$R_r \propto gap^4$$

- ❑ Capacitive gaps as small as **80nm** demonstrated



- ❑ **28% tuning** range for the 80nm gap device

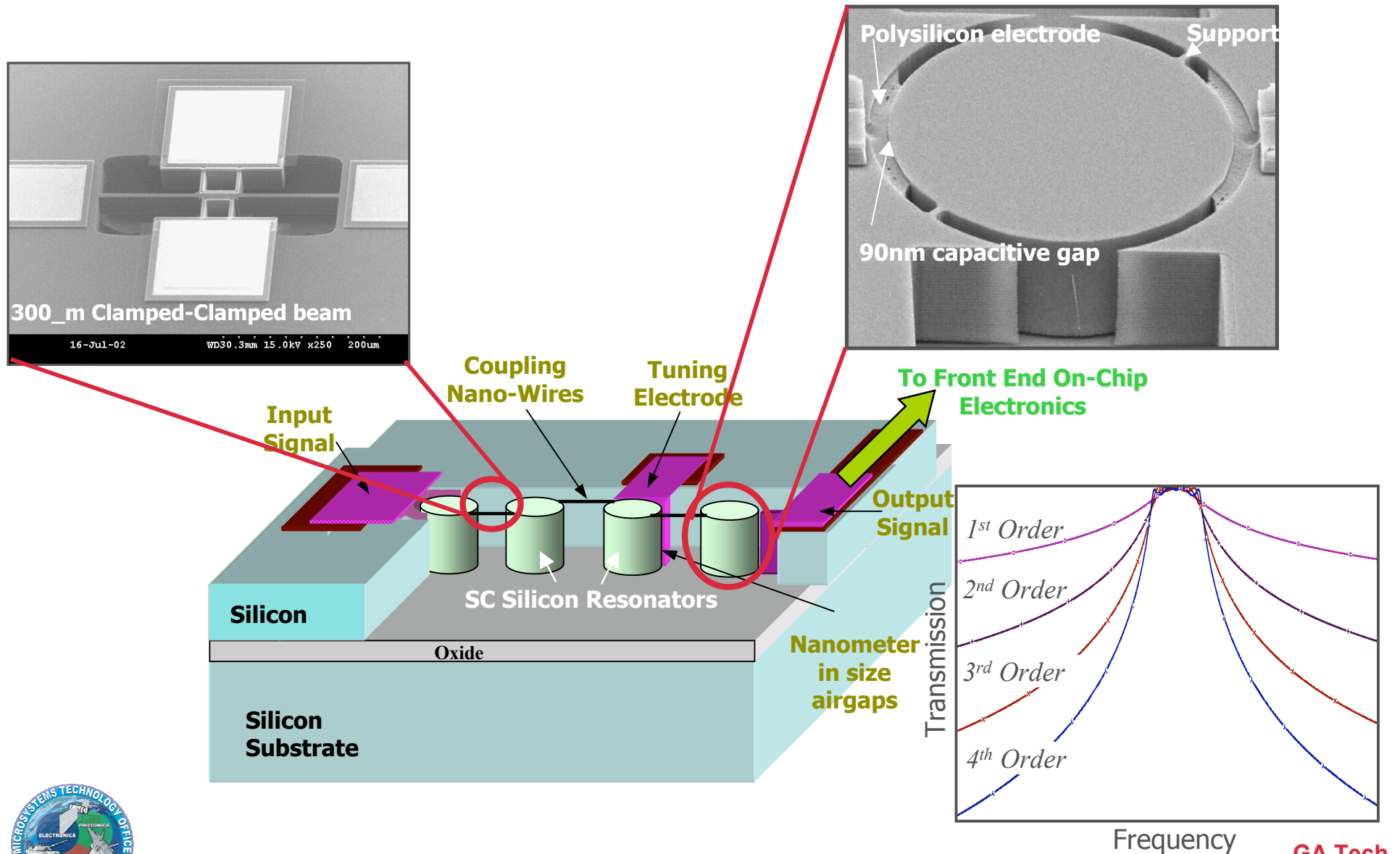


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# SOI Nano-scale Disk Resonator Arrays



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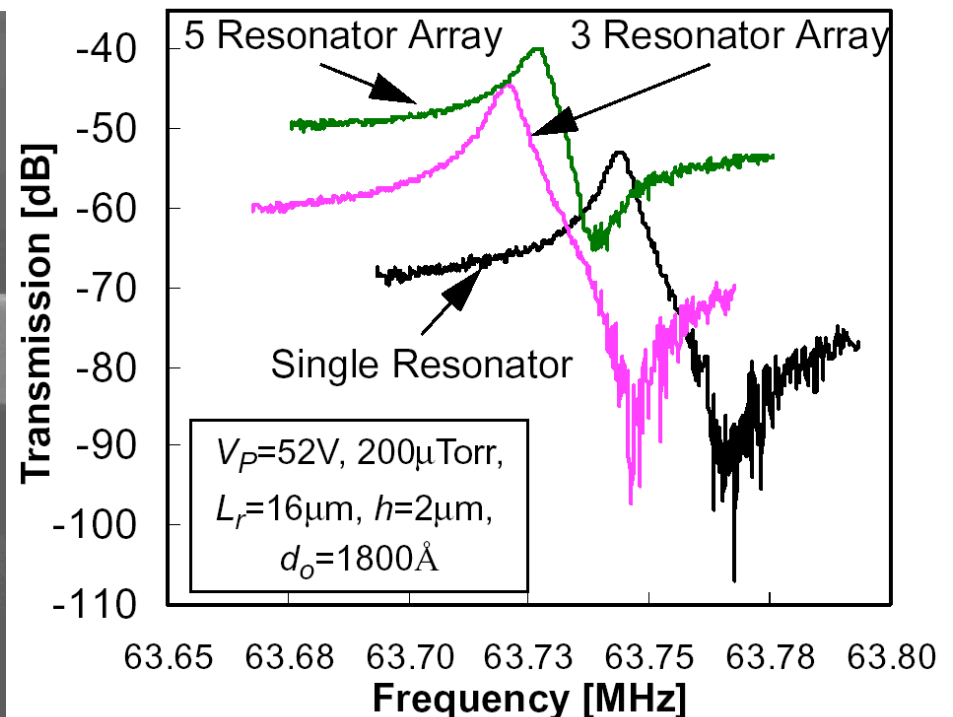
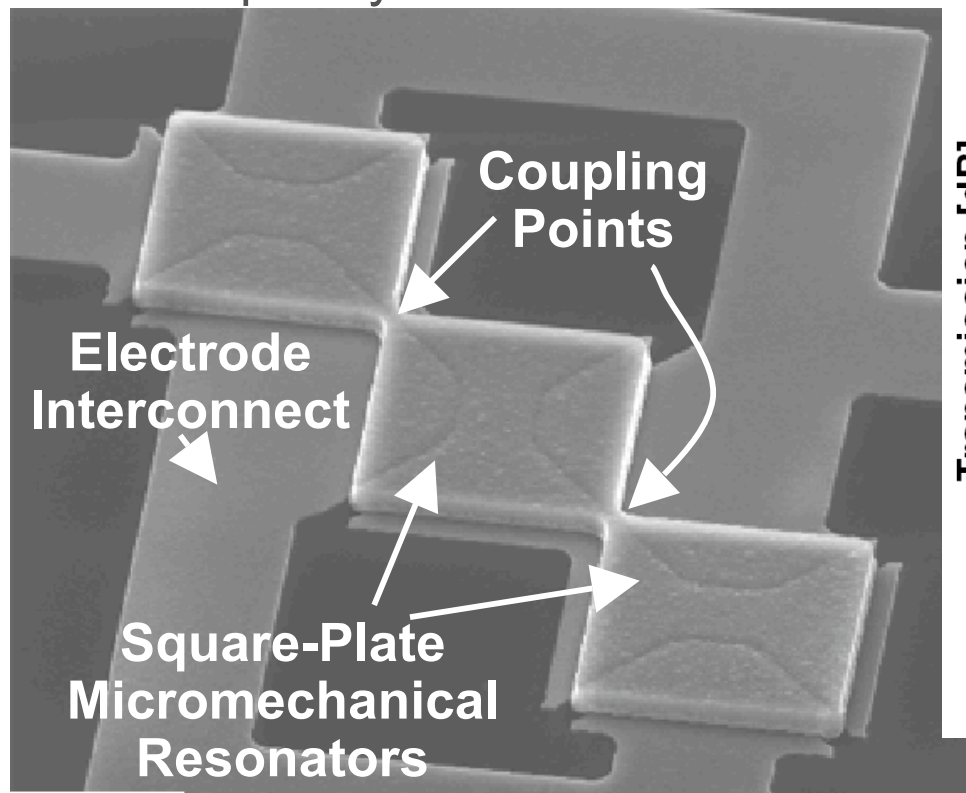
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GA Tech

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# Mechanically-Coupled Resonator Arrays for Higher Power Handling

- Problem: small size  $\Rightarrow$  lower power handling
- Solution: combine signals from an array of microresonators
  - problem: all resonators must be at the same frequency
  - solution: mechanically couple them to force all to resonate at the same frequency

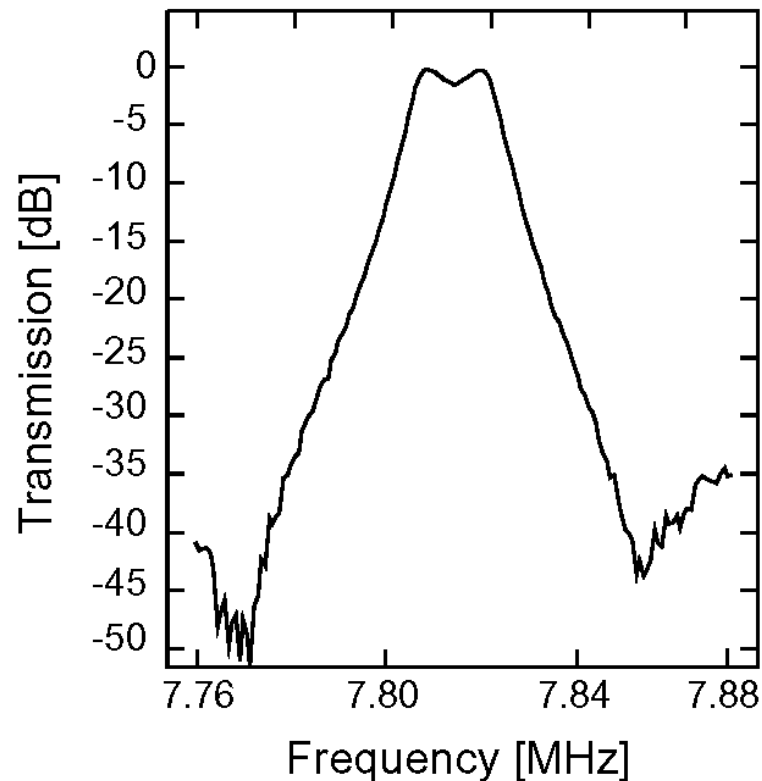


[Demirci, Nguyen 2003]

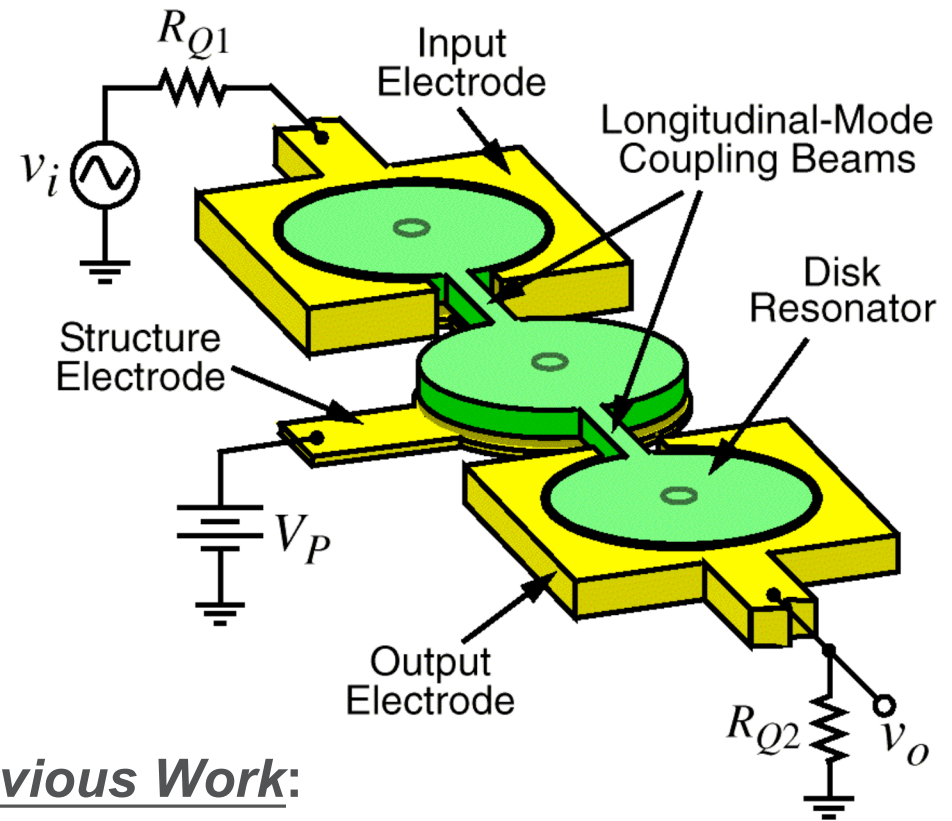


# Future Work: □Mechanical Filters

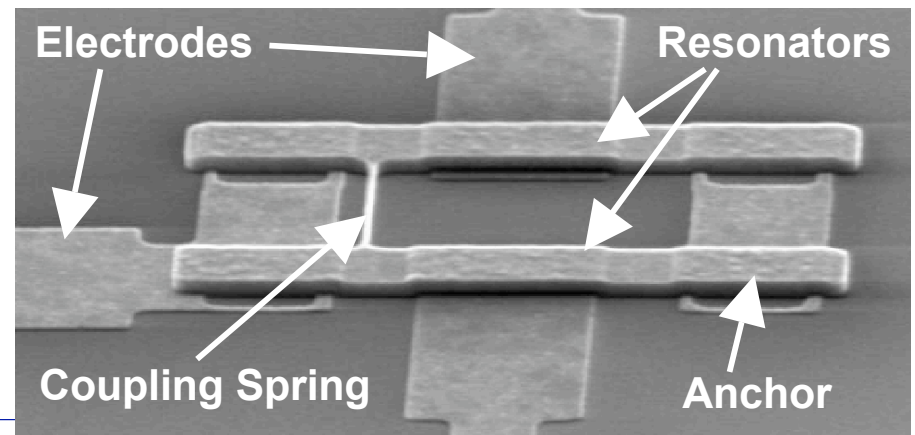
- Lower the impedance of GHz micromechanical resonators
- Create □mechanical circuits using such resonators
- Example: □mechanical filter



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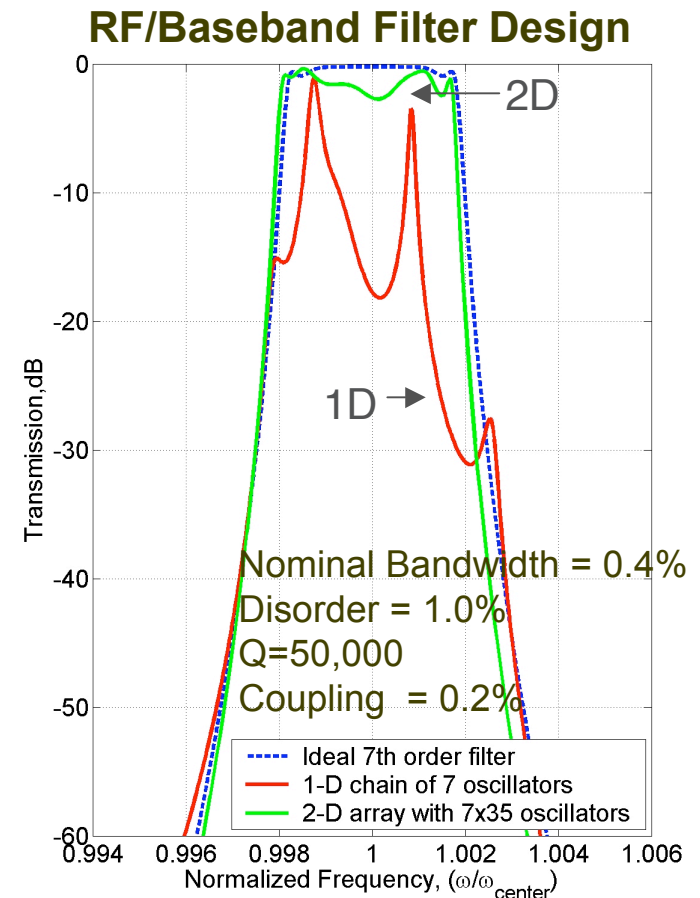
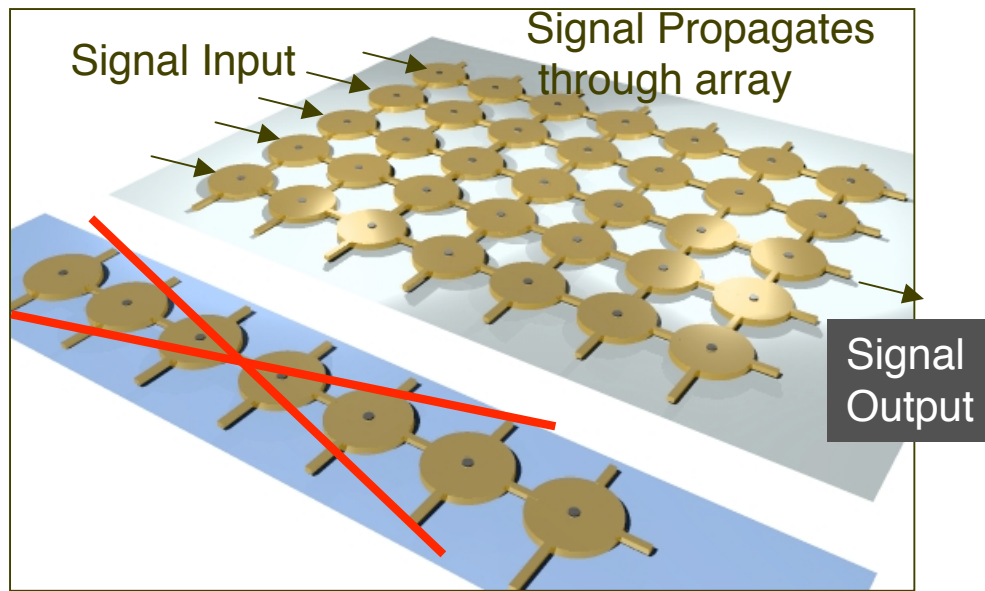


Previous Work:



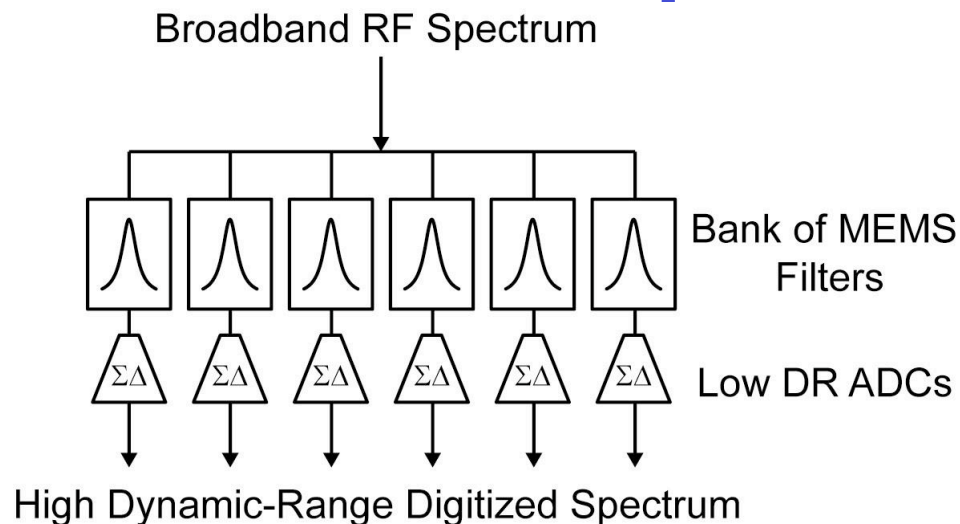
# Can Trimming be Avoided

- We have invented a 2-D array approach that allows disorder to be averaged in a second dimension resulting in significantly improved performance.
- Can “trimming” be avoided?

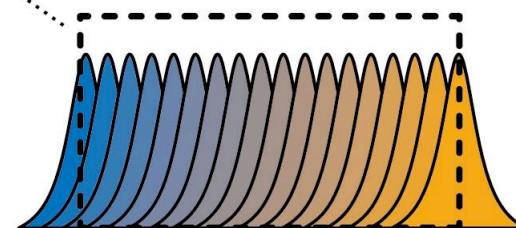


J. Judge, et al. in press

# MEMS RF Spectrum Analysis



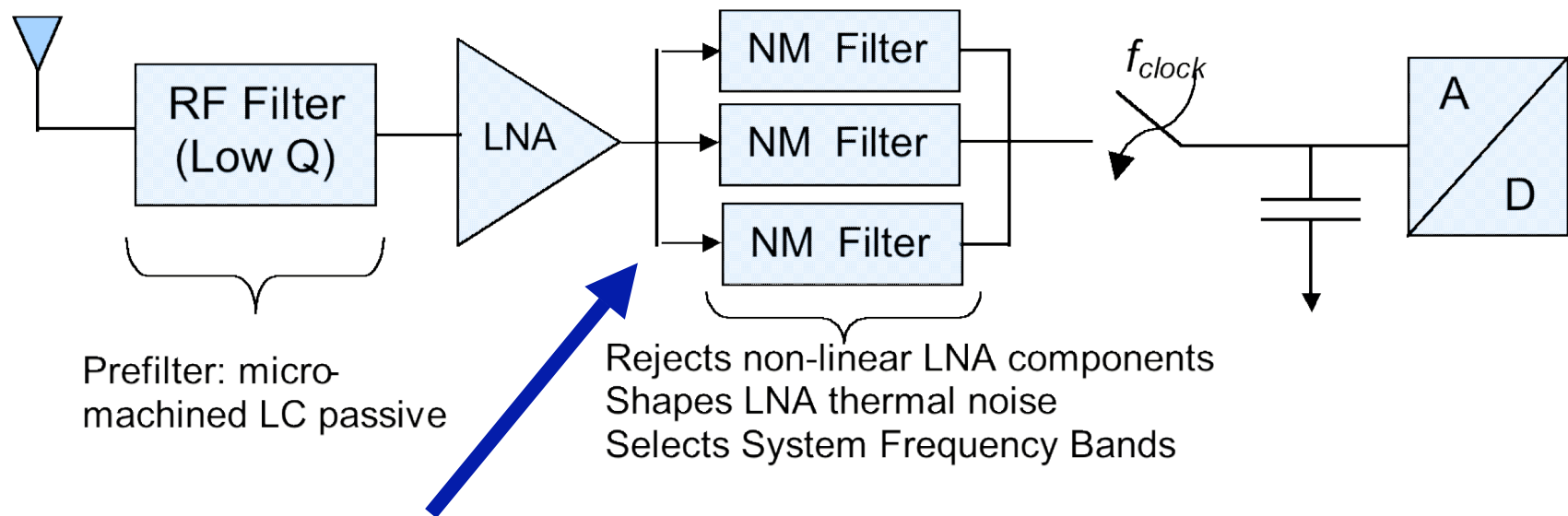
Desired Spectrum



- Broadband RF “digital” radio requires fast high, dynamic range ADC and broadband RF front-end
- Bank of active MEMS resonators selects narrowband signal
- Low performance  $\Sigma\Delta$  converters digitize each narrowband spectrum
- Relaxed requirements on ADC performance result in power savings and integration



# “Analog OFDM” Subsampling Transceiver Using NM Filters

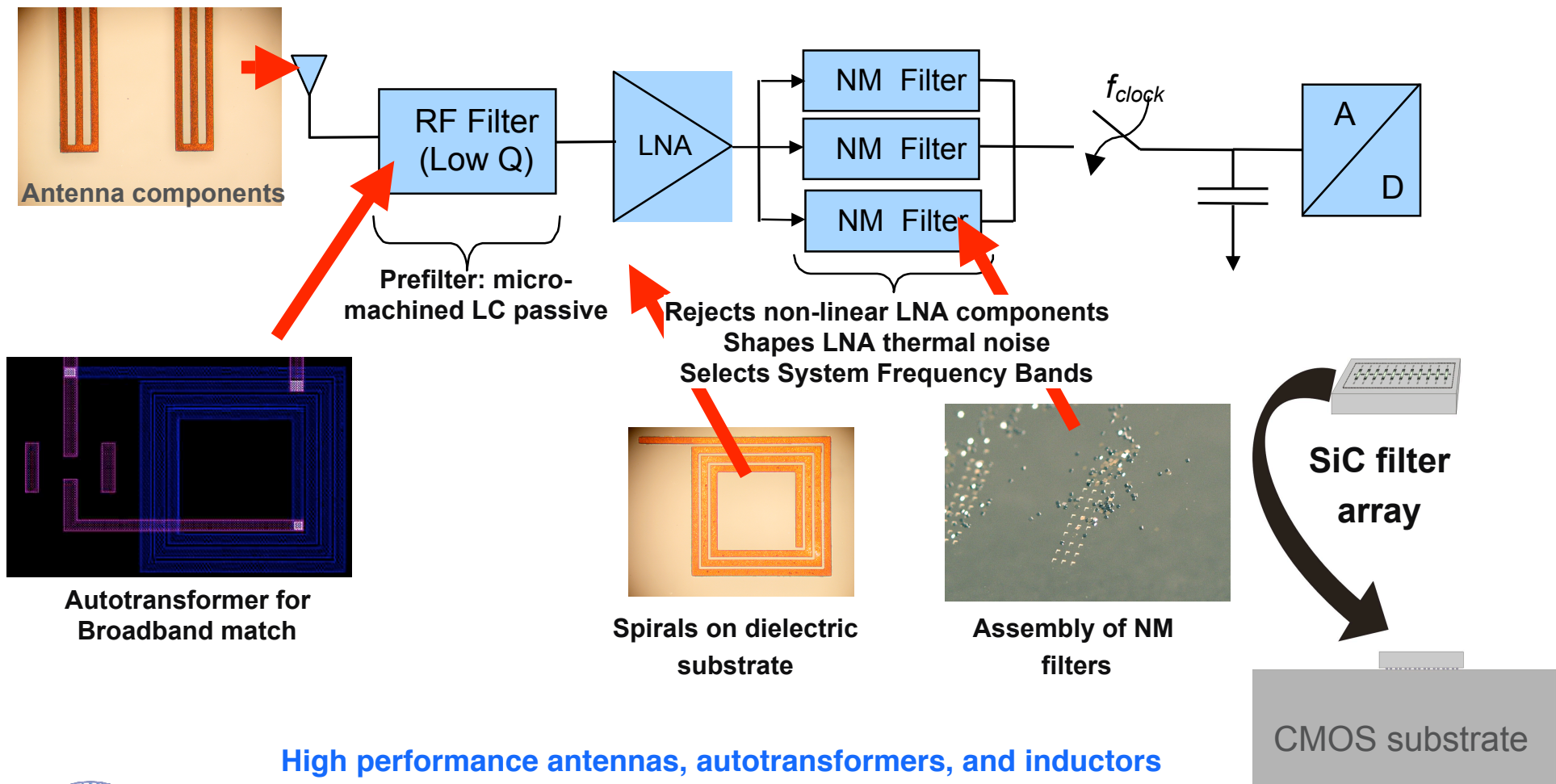


NM filters enable an integrated “comb”

Note: no local oscillator → reduced power



# Future Directions



High performance antennas, autotransformers, and inductors



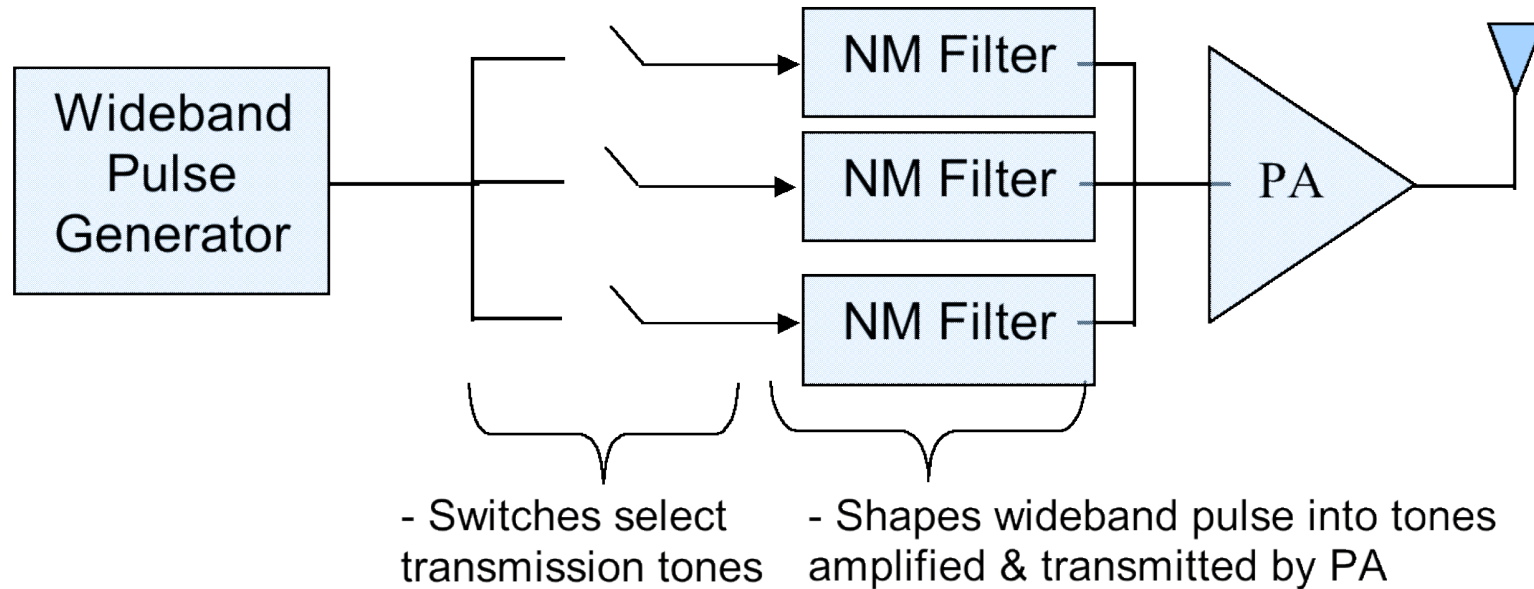
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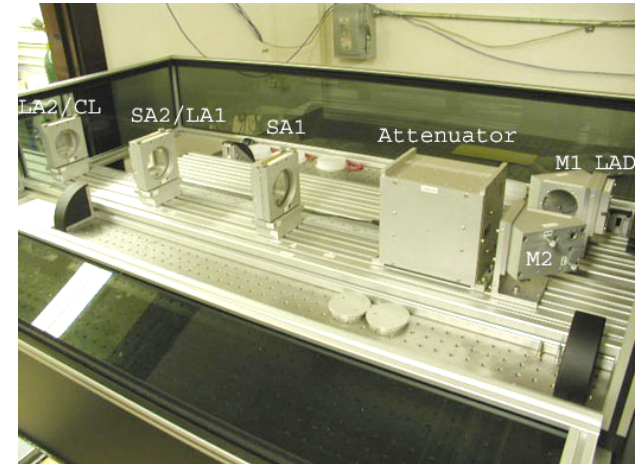
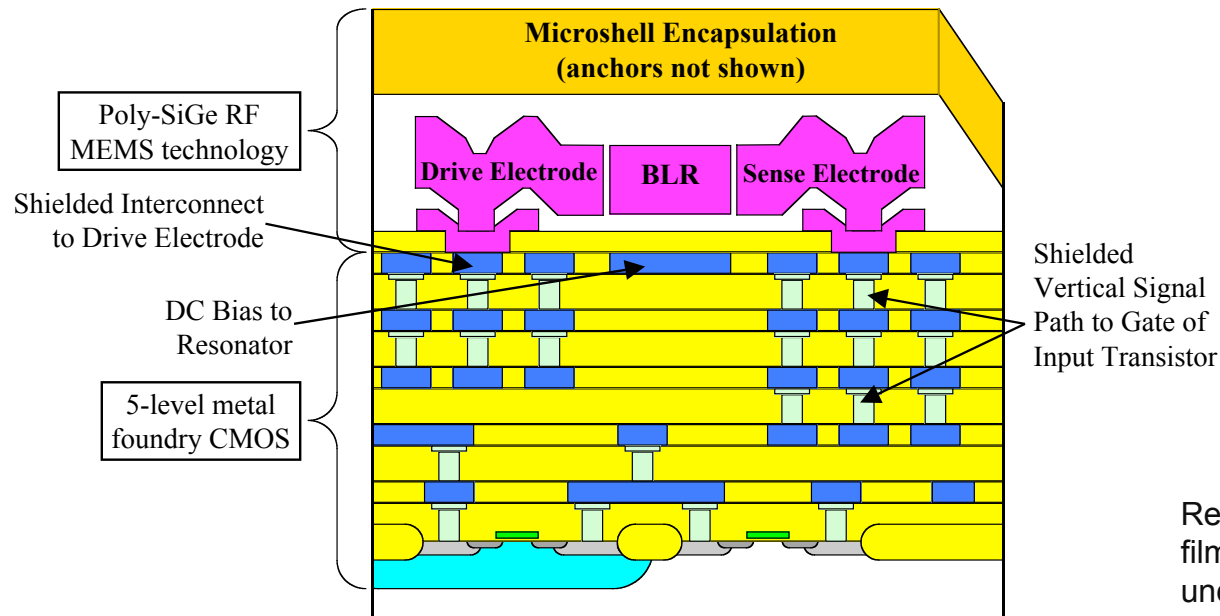
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# Transmitter Architecture

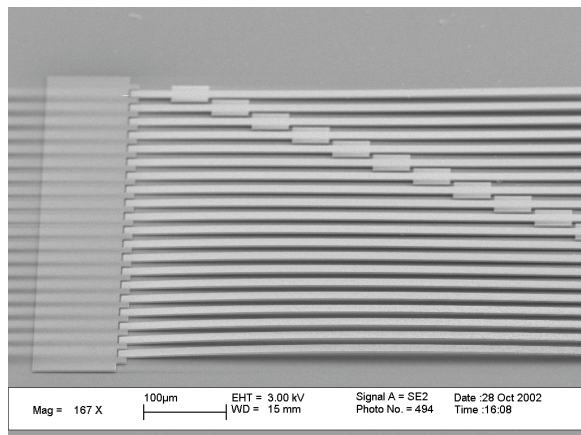




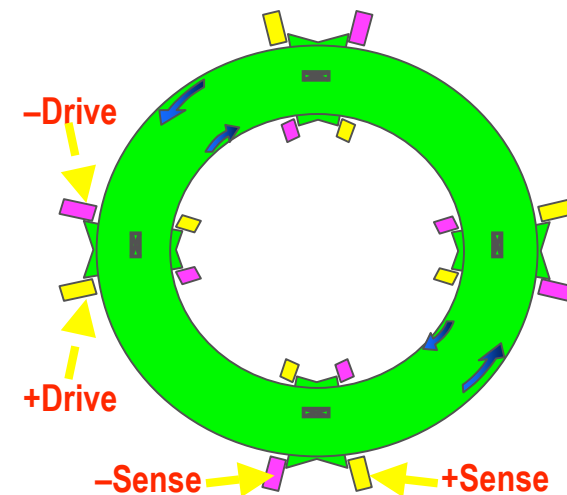
# Post-CMOS Poly-SiGe MEMS



Results (IEDM-02 and MRS Fall-02): 500 nm film can be re-crystallized without affecting underlying Al metallization



Bi-layer deposition process (2.8  $\mu$ m) to balance strain and strain gradient  
Residual stress: 3 MPa tensile



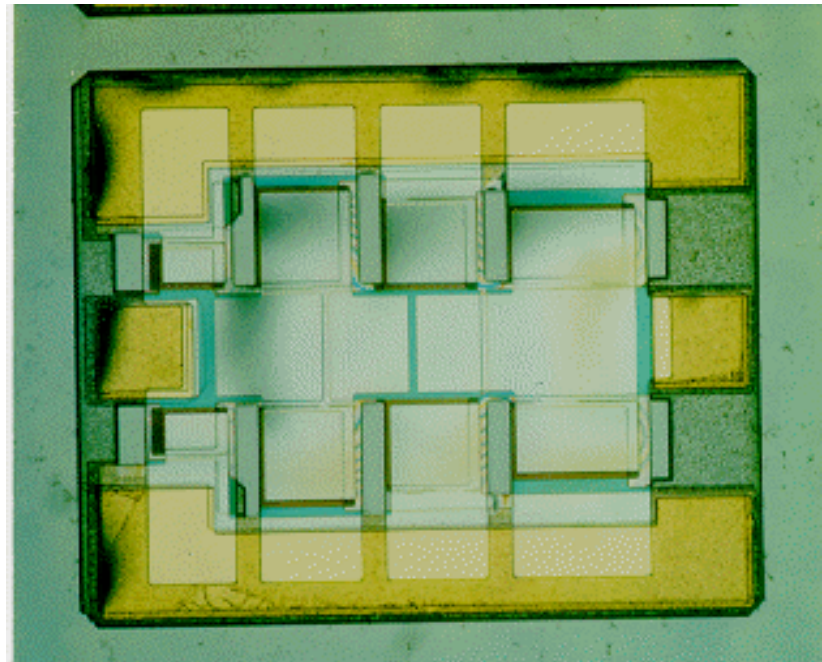
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# Thin-Film Bulk Acoustic Resonators

- Commercial off-the-shelf discrete components
- Frequency is a function of thickness → single frequency per FBAR chip
- Use to demonstrate new transceiver architectures

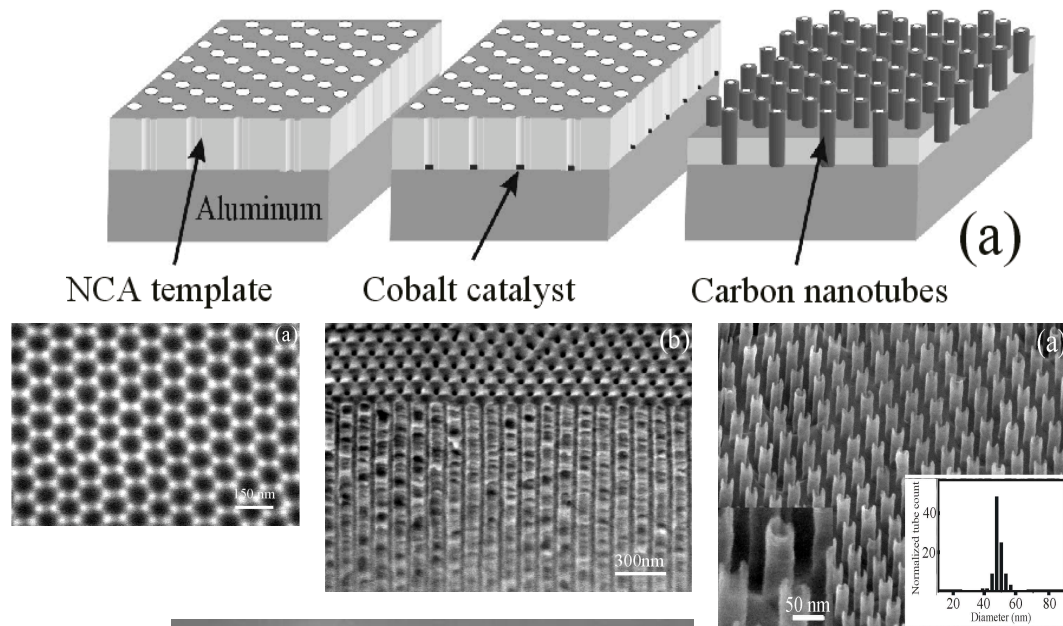


Agilent Technologies FBAR duplex filter

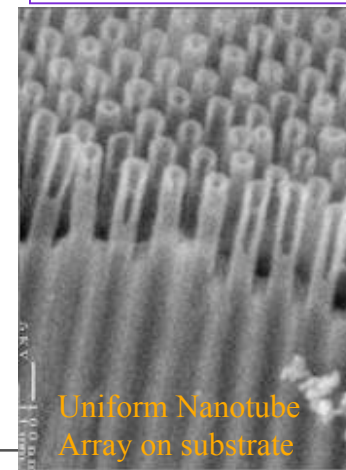
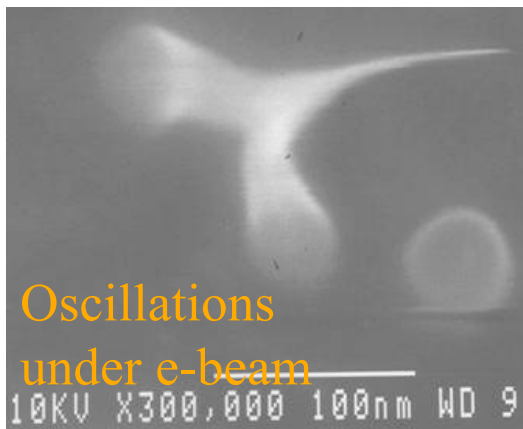
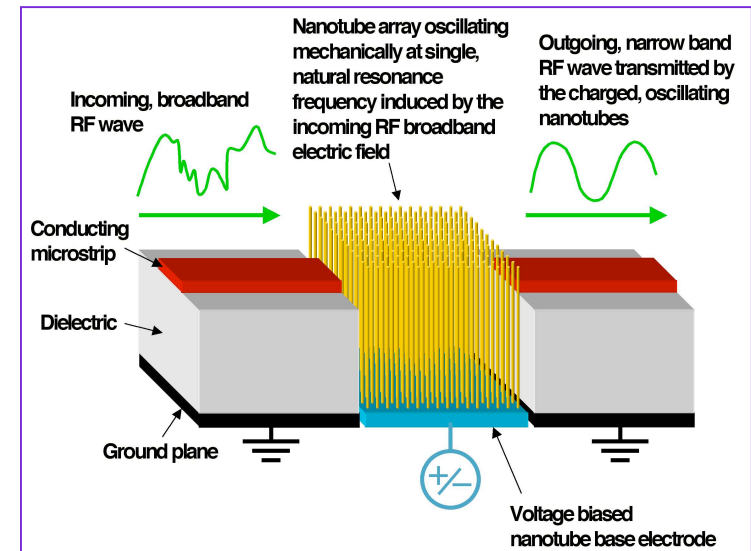


# Carbon Nanotube Filter

Al anodization → Co deposition → C<sub>2</sub>H<sub>4</sub> pyrolysis



## Nanotube Array RF Filter



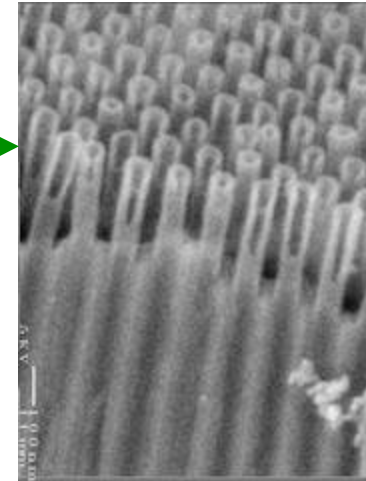
Creating and assembling a uniform array of MWCNT's for RF detection and filtering



Microsys

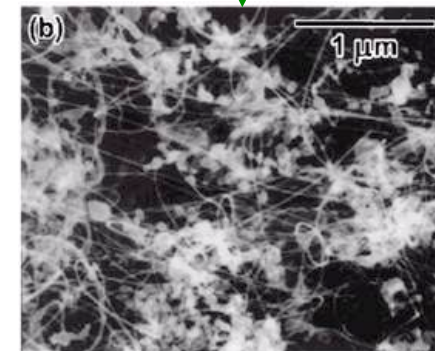
## CNT fab methods and results to date

Develop a base technology for fabricating ultra-uniform, highly-ordered and electrically accessible carbon nanotube arrays for the study & device applications.



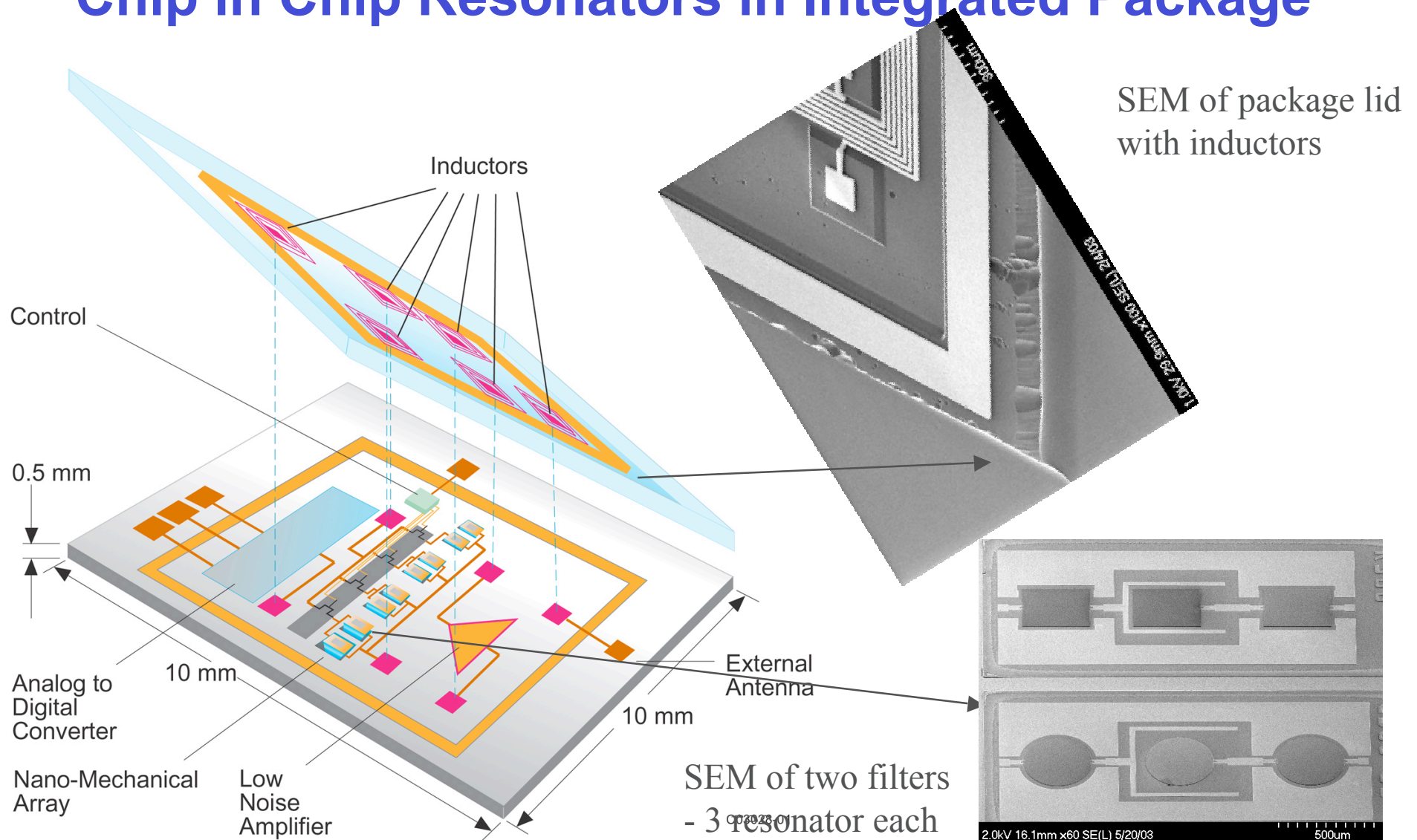
Results to date: *excellent uniformity and ordering (95%+), as well as excellent electrical, optical and mechanic accessibility.*

As compared to the best of conventional approaches





# Chip in Chip Resonators in Integrated Package



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# End Slide

- DARPA NMAASP Program in final phase
- High Q, nanoscale structures for RF resonators
- Nano-scale process technologies could be used in resonator fab, define gaps, coatings, etc.
- Need to think about how to get close to 50 Ohms

